

## Lisa 1.75 Diagnostic tests.

This document contains a simple description of the diagnostics performed by the Lisa 1.75 Diagnostic packages.

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### ROM Checksum test.

These tests are done in the Boot ROM and are to verify that the correct data was programmed into each ROM and that each ROM location is readable. This test calculates the checksum of each ROM, using the same method as the Lisa 1.0 Boot ROM, and verifies that each ROM is correct.

1. For ROM #1. This ROM is the one that contains the Startup and Diagnostic code. If this ROM is bad then a Boot ROM fatal error will occur right away.
  2. For ROM #2. This ROM contains hardware drivers and O.S. routines. If this ROM is bad then a fatal error will occur after all other diagnostics have been run.
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### Video Memory tests.

These tests assure that the screen area and the data area for the diagnostics are functioning properly. A failure here is fatal and will terminate testing.

1. Stuck-at tests, verifies that there are no stuck-at-one or stuck-at-zero memory locations.
2. Address uniqueness test, verifies that each memory location is unique and that no addresses are tied together.
3. Memory pattern tests, these tests look for other types of memory failures such as refresh fails.

*Extensive.* These tests are done in the Boot ROM. The Boot ROM uses the video memory as a data storage device and operation entirely from the CPU board, with no memory board plugged in, is essential for booting any device.

*Burn-in and hard to find problems.* This is a set of extended memory tests designed to be run from LisaTest. These tests run 'new and improved' pattern tests and are designed to catch very hard to find memory errors. These tests may run from only minutes, to hours, or days. The only way for these tests to be accessible are for the Boot ROM's own tests to have passed.

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### **Video circuitry tests.**

This is a basic test of the video circuit. Both screen modes are timed to assure that the video is switching properly.

#### **1. VRT/VID/CSYNC test.**

The hardware provides a two bits in the status register which allows a program to monitor the video signals generated by the CPU board. This program tries to determine whether the CPU board video circuitry is working by looking at the VID and CSYNC relationships.

The test checks to see that there are transitions on the VRT (Vertical Retrace) bit in the status register, and makes a rough estimate of the time between pulses on this signal.

The CSYNC bit is tested for transitions and the VID bit is checked to make sure it is static for a solid black screen. The number of CSYNC pulses between vertical retraces is checked.

The third routine first writes an alternating pattern of 1s and 0s to the screen memory area, 45 words of 0 then 45 words of 1, etc., until the area is filled. This will create a pattern on the screen of alternate white and blank lines. The routine then uses a scan routine to review the status register between 2 vertical retrace pulses, and analyses the resulting data for the correct signal patterns.

After this, the program tests the vertical retrace interrupt capability.

*Basic tests.* These tests are designed for the Boot ROM and determine if the Video circuit is basically working.

*Extensive timing tests.* These tests are to be run from LisaTest and the LMO station. These do more extensive timing measurements of the video signals.

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### **Serial number validity test.**

This is a simple check to assure that the serial number is in the proper format and that the serial number is readable. A bounds check is done on parts of the serial number, this is a very loose test to allow all valid numbers to go thru. If the serial number is not readable or outside of legal bounds then a fatal Boot ROM error occurs.

This test is only required in the Boot ROM.

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### **Timer tests.**

The timer is one of the most important parts of the system. The various

modes are tested for proper operation. A failure on either timer #0 or #1 will result in a fatal error for the Boot ROM. Since the timer #2 is used only for the speaker, its failure will result in a non-fatal error for the Boot ROM.

Timers #0, #1, and #2 will be tested (note: timer #2 does not generate interrupts).

1. Binary and BCD(Binary Coded Decimal) count modes.
2. Mode 0, Interrupt on terminal count.
3. Mode 1, Programmable One-Shot.
4. Mode 2, Rate Generator.
5. Mode 3, Square Wave Rate Generator.
6. Mode 4, Software Triggered Strobe.

*Extensive tests.* The Boot ROM will extensively test the timers for proper operation. These tests will test all of the modes above.

*More extensive tests.* More tests for the timers may be added to run thru LisaTest or LMO if the tests in the Boot ROM tests are not extensive enough.

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#### **COPS functional tests.**

This is the device used to talk to the Keyboard and the Mouse. It also handles other items such as the time of day and programmable alarms.

##### **1. Setable test.**

The calendar control allows anyone to disable the calendar, which is done when it is being set. The first test is one to make sure that the calendar can be properly set. The calendar is disabled during this subtest, this assures that when it is set it will not change before the program has enough time to read it and see if it has been set properly.

The test sets the clock to many different values to assure that each part of the date is set to the correct values. The COPS is sent the date to be set and then the command is sent to the COPS to return the current date. Since the clock is disabled, the value set and the value returned will be the same.

##### **2. Wraparound test.**

This next test assures that the calendar keeps track of the time correctly. This assures that, for example, when the seconds go from 59 to 60 seconds that the calendar changes the seconds from 59 to 0 and increments the minutes by one. All the calendar parameters are tested to wraparound at the correct values. Other values are tested to assure that standard incrementing is done.

To do this test, the calendar is set to the test value, the calendar is enabled so it will increment every one tenth of a second. The program then waits for a little over one tenth of a second and then reads the current calendar time. Since the clock time should have changed, the time read will reflect the wraparound of parameters.

##### **3. Alarm test.**

The COPS device also contains a programmable alarm. The user can specify that an alarm be generated, in effect that the computer is interrupted by the COPS, after a specific amount of time. The resolution of the alarm is one second. The alarm is set, the program waits for the programmed time plus 3

seconds or until the interrupt occurs. The time expired from when the alarm was set and when the interrupt happened is verified against the actual programmed time.

4. Internal register tests.

Registers internal to the COPS are tested here.

5. Keyboard reset function.

The keyboard is reset by the COPS and the correct reset code is read. This value is compared to the reset code that was sent to the COPS on powerup.

*Clock functional tests.* These tests are for LisaTest and LMO stations. These do a complete functional check on the COPS and associated timing.

*Keyboard reset code tests.* These tests are simple functional tests that do not change any data (for example the date and time) and do only a basic check of the COPS. These tests are for all test areas, LisaTest and LMO and Boot ROM.

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**IWM diagnostic test.**

This test tries to assure that the IWM chip and associated hardware on the CPU board is functional. It is a minimal test of this floppy interface since it is done whether or not a disk is in place and must assume that there is not a disk in place.

1. (To be determined)
2. (To be determined)
3. (To be determined)

*Basic tests for IWM.* These tests are tests of the IWM circuit and assume that the drive does not have a diskette installed, these tests are for CPU board LMO stations and for the Boot ROM.

*Extensive tests for the IWM circuit going to the drive itself.* These tests are for the IWM circuit and require that a drive and disk be installed, see the next test description.

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**Floppy disk tests.**

These tests verify the proper operation of the floppy disk drive and complete the testing of the IWM and interface hardware. Since a floppy drive and disk are required to completely test the IWM circuit, these tests are required in the LMO station and LisaTest. Because of a Field Service requirement that the floppy drive be completely debugged from the Boot ROM, a subset of these tests will be in the Boot ROM as space permits.

1. (To be determined)
2. (To be determined)
3. (To be determined)

*Basic tests for IWM and Interface.* These tests are tests of the IWM circuit and may have to assume that the drive is good, these tests are for CPU board LMO

stations.

*Extensive tests for drive itself.* These tests are for the drive itself and may have to assume that the IWM circuit is good.

Note that there may be cases where both the IWM interface and the drive itself are unknowns. The tests must take this into consideration. But note that the best way to troubleshoot this case is to swap out the floppy drive (a simple procedure) and then re-run the test that has failed. This narrows the failure down to either the IWM circuit or the floppy. Once it is narrowed down then the tests for that specific circuit or device can be run to isolate the failure further.

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#### RS232 tests.

These two serial ports are tested extensively for the most common modes that they will be used in. The ports own internal loopback feature helps to ensure a more complete test.

Port A and Port B.

- A) Register read/write tests.
- B) Local loopback tests.
  - a) Async test.
  - b) Sync test.
  - c) SDLC test.
- C) External loopback tests.
- D) Interrupt test.

#### A) Read/Write Test

This first module writes an \$AA data pattern to an internal read/write register in Port A and then reads it back and verifies its integrity. It then repeats the process with a \$55 pattern. Both patterns are then tested on port B. The main purpose of this test module is to verify that it is possible to access this device (i.e. it exists in valid address space). A special bus error trap is provided to retain control of the program in the event that the device is not readily accessible.

#### B) Internal Transmit/Receive Test

Here, the SCC device is tested for its ability to transmit and receive in asynchronous mode. The test is performed at 19200 baud using the internal loop (built in), therefore no external drivers are being tested as of yet. The data format is 8 bits, 1 stop bit, internal baud rate clock x16 mode, and odd parity. All possible 8 bit characters are used and each is checked for data integrity upon reception. Also after each character is transmitted the program waits for the "all sent" flag, data received flag, and then checks for special error conditions such as framing, parity, and overrun.

#### C) External Transmit/Receive Test

Here, the SCC device is tested for its ability to transmit and receive. The test is performed at all baud rates using the external loopback connector, therefore external drivers are being tested here. The data format is 8 bits, 1 stop bit, internal baud rate clock x16 mode, and odd parity. All possible 8 bit characters are used and each is checked for data integrity upon reception. Also

after each character is transmitted the program waits for the "all sent" flag, data received flag, and then checks for special error conditions such as framing, parity, and overrun.

#### D) Interrupt Test.

Tests the ability of the SCC device to interrupt the system processor. First a dummy interrupt routine is setup to handle the interrupt. This routine resets the source of the interrupt in the SCC and restores the normal vector in the vector table. A default timeout is then set in the baud rate timer in the SCC and the device is programmed to interrupt the system processor on timeout. The system then begins a count and patiently awaits the expected interrupt.

*Basic tests.* These tests are the basics done to assure the ports work properly and will not drive any test data out the ports. These use the internal loopback feature and the latch that disables data going out the rear ports.

*External tests (required loopback).* These tests check the port in more of a 'natural' manner, in the way it is normally used.

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#### MMU tests.

If a memory board is installed then this test is done to verify that the board can be mapped as the user requests.

1. Stuck-at tests, verifies that there are no stuck-at-one or stuck-at-zero memory locations.
2. Address uniqueness test, verifies that each memory location is unique and that no addresses are tied together.
3. Memory pattern tests, these tests look for other types of memory failures.

*Basic pattern & functional tests.* These tests are done by the Boot ROM and must pass for the boot process to continue. It may still be possible to do a auto-boot procedure on detailed diagnostics.

*Extensive tests.* These tests help to isolate failures to the chip. If space requirements prevent the Boot ROM diagnostics from isolating the failure far enough then these more extensive tests will do that task. These tests also do more extensive memory tests on the MMU RAMs.

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#### Parity Circuit test.

This test verifies the memory parity check and generation circuits.

##### 1. Parity detection test.

This program tests the capability of the CPU board to write wrong parity, (for diagnostic purposes), the Parity bit RAMs, and the failing memory address register. Parity is a method used in computers to assure that data stored in

memory is correct. The common method of using parity is for the computer to count how many bits are on at each memory location and then add one if necessary, in the parity bit, to make it an odd number or leave the parity bit set to 0 if it already contains an odd number of bits on. Example:

Odd parity example:

Memory Data	Parity bit	# bits set
10001100000	0	3
10001110011	1	7

Using the capability of the CPU board to write wrong parity, the number of bits set above would be 4, parity bit set to 1, and 6, parity bit set to 0.

When the computer senses that a memory location being used contains the wrong parity bit, it assumes that the memory data has been changed in some way from the data that was written. When this error occurs the CPU board tells the computer about the error and also which memory location contains the error, this address is in the Failing Memory Address register.

This test uses the special circuit on the CPU board to set the wrong parity on some locations in memory, the parity detection circuit is disabled at this time. Parity detection is then enabled and the memory locations are read. Each location which has been set to the wrong parity is verified to generate a parity error and the failing address is checked.

2. This is a test of the parity memories. These RAMs are tested in a special way since they must be 'written' and 'read' indirectly. These extended tests are very long because of the method that must be used.

### 3. Bus Timeout.

The last test is that for the bus timeout circuitry. If illegal memory, memory which is not in the system but still within legal address range, is accessed then a bus timeout will occur. The computer must receive a signal back each time it addresses a location in memory. If the memory is not there then no signal is returned to the computer and the computer would sit and wait for the memory. To prevent the computer waiting forever, a timer is used to limit the length of time that the computer will wait.

*Basic functional tests.* These tests are in the Boot ROM and assure the basic operation of the functions described above.

*Extensive tests.* These are very extensive tests to determine parity circuit memory errors along with parity circuit errors.

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### Main Memory tests.

These tests perform a quick check of the memory. An optional extensive memory test is available thru the boot device code.

1. Stuck-at tests, verifies that there are no stuck-at-one or stuck-at-zero memory locations.

2. Address uniqueness test, verifies that each memory location is unique

and that no addresses are tied together.

3. Memory pattern tests, these tests look for other types of memory failures.

*Basic tests.* These tests reside in the Boot ROM and consist of tests in two classes. The first class are 'Stuck-at' and 'address' tests that are very fast and are run every time the system is booted up. The second class are 'memory pattern' tests that usually run a long time and are optional thru the Service mode.

*Extensive tests.* These are additional tests which run more 'exotic' patterns. These tests are loadable thru LisaTest or an Auto-boot diskette.

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#### Additional MMU tests.

A functional test of the MMUs operation is done to assure that what goes into the MMU control, in the way of an address, actually has the desired effect. These are more extensive 'adder' tests.

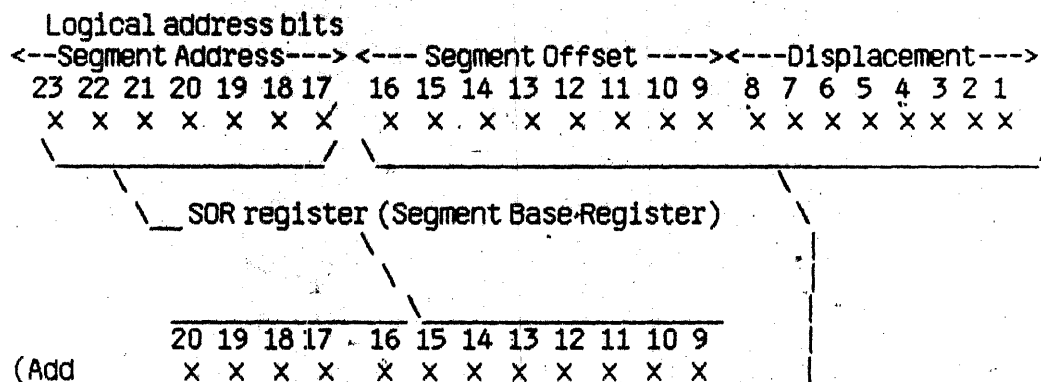
##### 1. MMU functional tests.

The MMU also can allow limited access to areas of memory. Memory can be specified as read only, so valuable information will not be destroyed, as write only, or as both read and writeable.

To convert a logical address, one which will work as described above, to a physical address, a real address that a memory board will recognize. A series of adders are used as shown below:

Logical address bits  
<---Segment Address---><---Segment Offset---><-----Displacement---->  
23 22 21 20 19 18 17 16 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

The Segment Address addresses a register which contains a physical (real) address, this is called a Base address. This physical address contains valid bits in the bit 9 to bit 20 range, this is enough to access 2 Meg bytes of memory. This value is then added to the Logical address bits 0 to bit 16. The resultant address is the corresponding physical (real) address. See the example below:







boot time, or if the hard disk was selected as the boot device. Other tests are designed as described below.

*Non-destructive tests.* These tests are for use with the disk's internal diagnostics. The disk has the capability of returning the status of it's own internal diagnostics. The disk may also have other internal diagnostic capabilities that can be used without destroying any data on the disk.

*Extensive destructive tests.* These disk tests are destructive in nature and would be used only after all information has been backed up off of a suspected bad disk. These may also be run on a new disk before the Office System is backed up onto it.

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#### **Expansion card diagnostics.**

Each expansion card has the capability of having its own diagnostic in a ROM that is part of that card. If a diagnostic resides on the card then it will be run as part of the normal Boot process, by the Boot ROM. If the card is also bootable, then if the card fails it's own internal diagnostic test it is made into an illegal boot device by the Boot ROM and the user will not be allowed to boot from it.

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#### **Speaker voltage tests (test card).**

Designed to run from LisaTest or from an LMO station. This test will be identical in function as that on Lisa 1.0 systems. It basically tests the volume control and frequency of the signal that is sent directly to the speaker. While it can not tell if the speaker is working, it can not find a broken wire from the board to the speaker or a torn speaker, it can tell if the circuit that generates the speaker voltages is correct.

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#### **MAC sound voltage tests (test card).**

Designed to run from LisaTest or from an LMO station. These tests are really enhancements to the 'Speaker voltage tests' described above. This test verifies that there is proper control of the sound signal by doing 'real time' measurements of the speaker voltage.

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#### **Contrast voltage tests (test card).**

Designed to run from LisaTest or from an LMO station. This test will be identical in function as that on Lisa 1.0 systems. This tests that the contrast voltage can be changed in a smooth manner from a dark screen to a very bright screen, within the required voltage specifications.

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**Mouse port tests (test card).**

Designed to run from LisaTest or from an LMO station. This test will be identical in function as that on Lisa 1.0 systems. This test uses the I/O Port Test card to simulate a mouse. All features of the COPS directly related to the Mouse are tested here.

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**Keyboard port tests (test card).**

Designed to run from LisaTest or from an LMO station. This test will be identical in function as that on Lisa 1.0 systems. This test uses the I/O Port Test card to simulate a keyboard. The COPS/keyboard interface is tested by sending the COPS a series of keyboard reset codes. This tests the timing of the keyboard interface and also verifies that the COPS can properly receive serial key codes from the keyboard.

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**DMA functional tests (test card).**

Designed to run from LisaTest or from an LMO station. This test will be identical in function as that on Lisa 1.0 systems. This test uses the famous 'DMA Test Card' to verify that the DMA circuit works properly in the system.

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**C.Itoh Printer test.**

Designed to run from LisaTest. This test will be identical in function as that on Lisa 1.0 systems. This is a confidence test of the printer and verifies all printer functions, those currently used and all others.

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**Qume Printer test.**

Designed to run from LisaTest. This test will be identical in function as that on Lisa 1.0 systems. This is a confidence test of the printer and verifies all printer functions, those currently used and all others.

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**Mouse interactive test.**

Designed to run from LisaTest. This test will be identical in function as that on Lisa 1.0 systems. This test is designed to test the Mouse for slipping, bumps and dents in the mouse ball, and button bounce. It also checks movements and measures the amount of pulses that the COPS has received.

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**Keyboard interactive test.**

Designed to run from LisaTest. This test will be identical in function as that on Lisa 1.0 systems. This test is designed to look for bad keys in the keyboard. These bad keys consist of key bounce, sticking keys, dead keys, and keys that give the wrong keycode back to the system.

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**Floppy disk controller card test.**

*No loopback required.* This test is similar to the diagnostic that will be built-in to this card's boot ROM. It does a test of the card with the assumption that something is connected on the other end and that 'something' must not be damaged.

*Loopback required.* This test is really a complete test of the board. Loopback capability is required to do a complete test. This card is currently in design and test specifics have yet to be defined.

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**Two-port card test.**

*No loopback required.* This test is similar to the diagnostic that will be built-in to this card's boot ROM. It does a test of the card with the assumption that something is connected on the other end and that 'something' must not be damaged. The two main devices, 6522s, are the main target of this test.

*Loopback required.* This test is really a complete test of the board. Loopback capability is required to do a complete test. What this test's main purpose is, is to check the port connections and do a continuity test of the lines from the 6522 devices out to the card's external connectors.

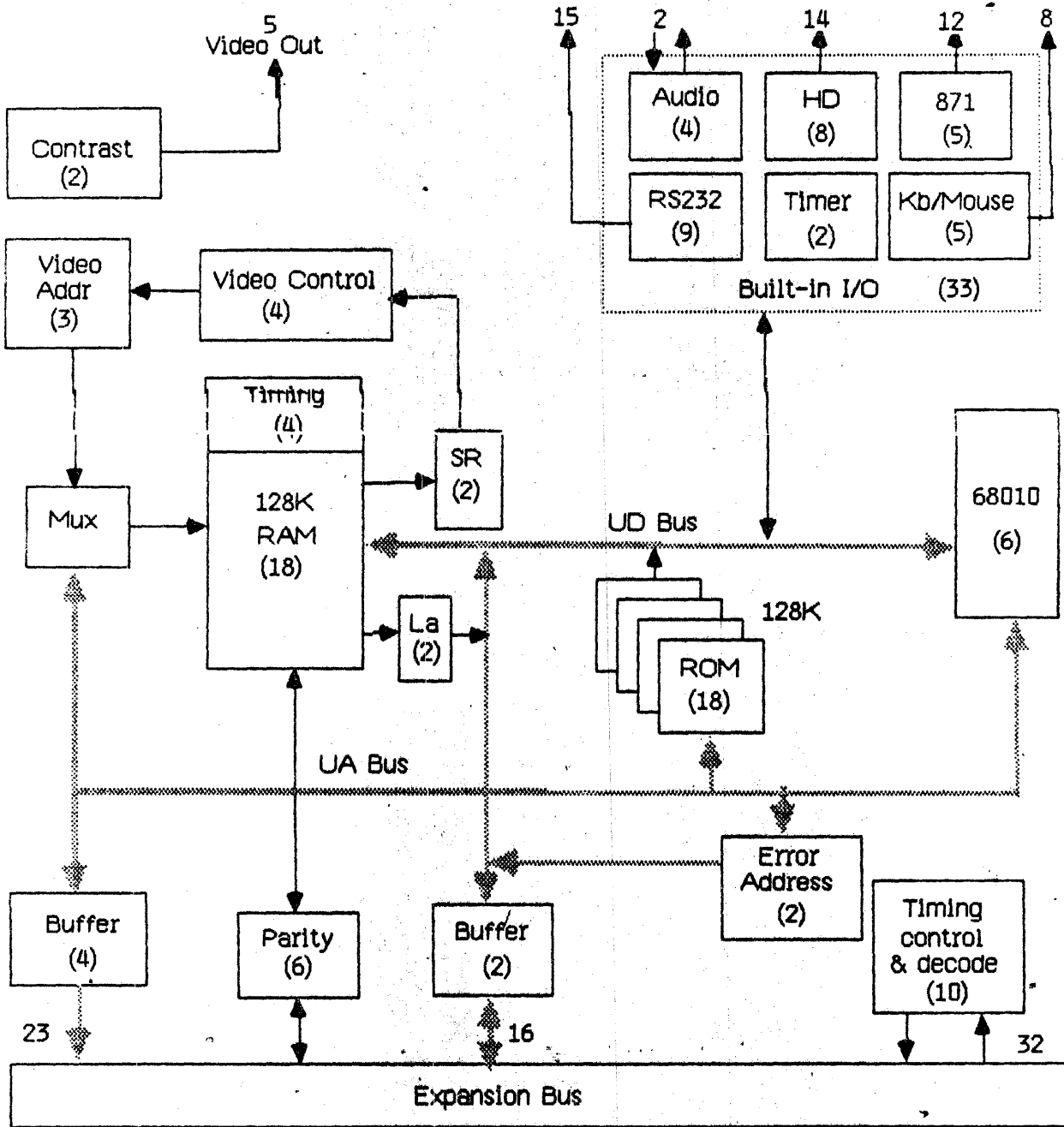
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**AppleNet card test.**

*No loopback required.* To be defined.

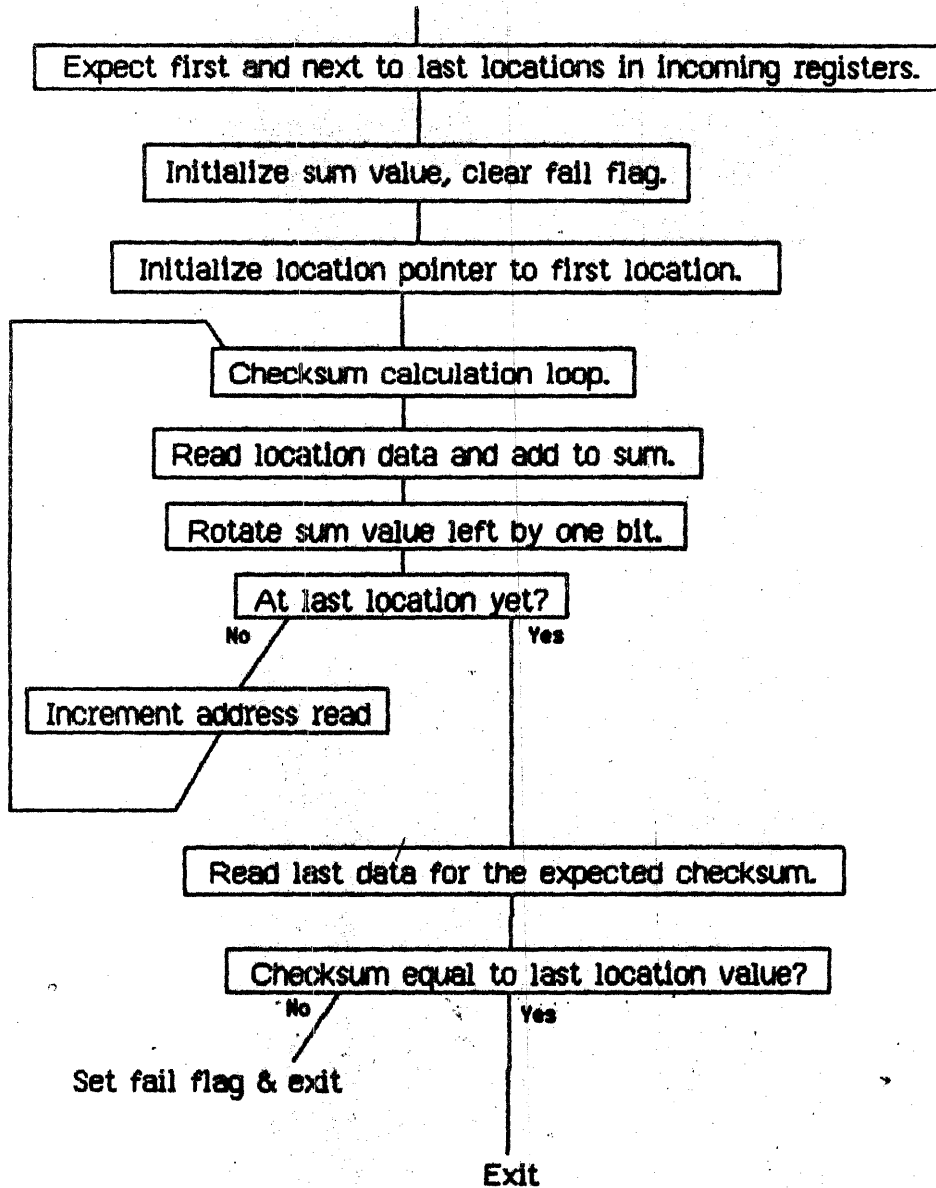
*Loopback required.* To be defined.

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**LISA 1.75 CPU BOARD**

# Checksum calculations



```
; Edit date: 08/03/83
```

```
; This program does a checksum test on any area of memory.
```

```
; Inputs:  
; a0 = First location  
; a1 = Last location
```

```
; Outputs:  
; d0 = Expected checksum  
; d1 = Actual checksum
```

```
; CheckSum
```

```
clr.l d1 ;clear for checksum use  
@1 add.w (a0)+,d1 ;read location and add to sum  
rol #1,d1 ;rotate to catch multiple bit errors  
cmpa.l a0,a1 ;loop until done  
bne.s @1  
move.w (a0)+,d0 ;Expected checksum word  
rts
```

# Timer #0 Test

Write mode register at \$004007  
Load counter #0 at \$004001  
Read counter #0 at \$004001

Load both bytes  
Load only LSB byte  
Load only MSB byte

16 bit counter mode  
BCD counter mode

Read both bytes  
Read only LSB byte  
Read only MSB byte

## Initialize chip

All placed in mode 2.  
All low bytes written to 0, disables counting & turns off interrupt request.  
All placed in mode 0.

## Basic register test.

LSB register test.

Write test value to LSB.  
Read value from LSB & compare.  
Abort test loop on failure.

MSB register test.

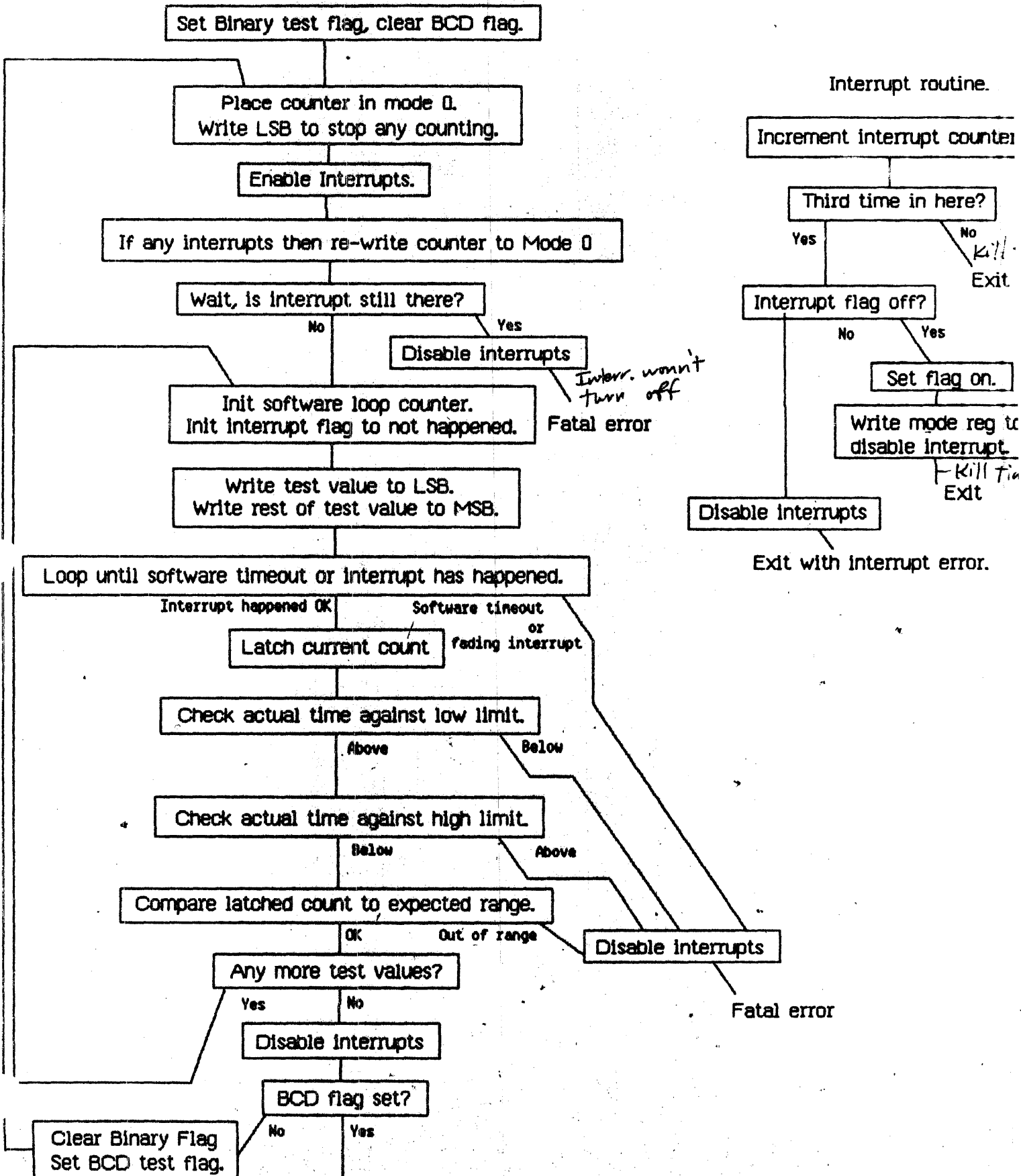
Place counter in mode 0.

Write LSB to max value, allows time to do other steps before MSB decrements.  
Write MSB to test value.  
Latch counter value.  
Write LSB to stop counting.  
Read latched count and compare MSB to expected.  
Abort test loop on failure.



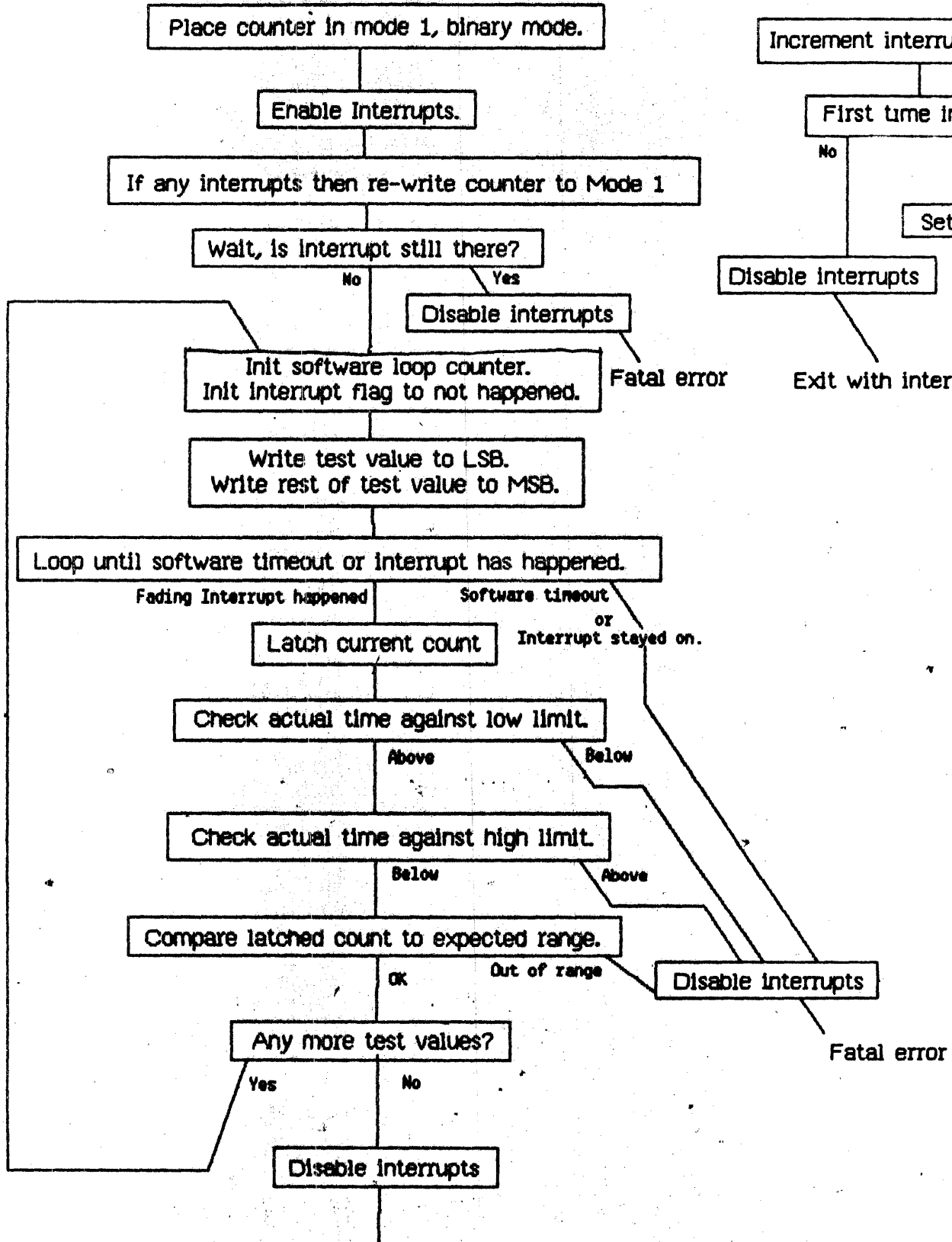
# Mode 0 test.

(0) Interrupt on terminal count mode.



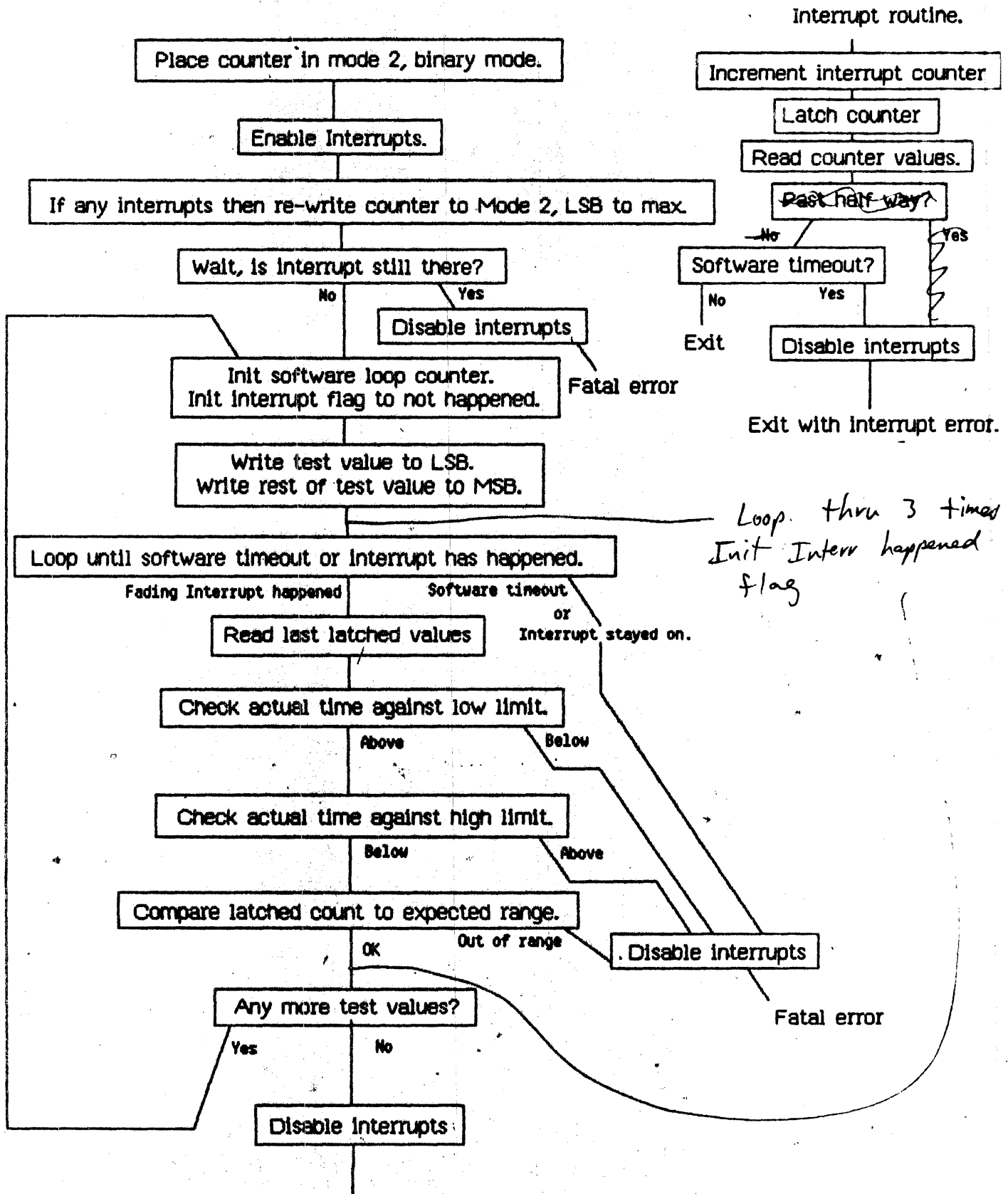
# Mode 1 test.

(1) Programmable One-Shot mode.



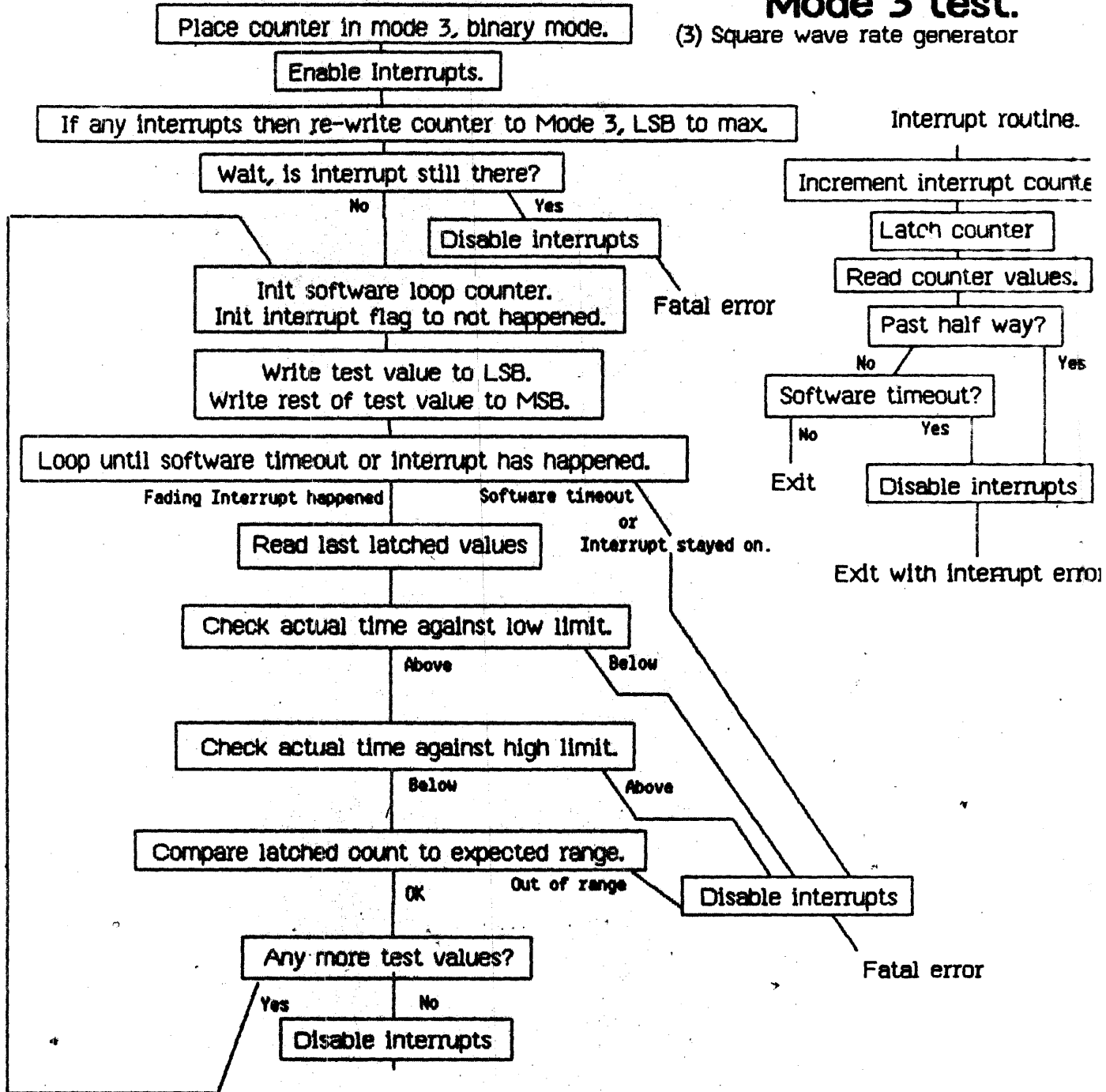
# Mode 2 test.

(2) Rate Generator mode.



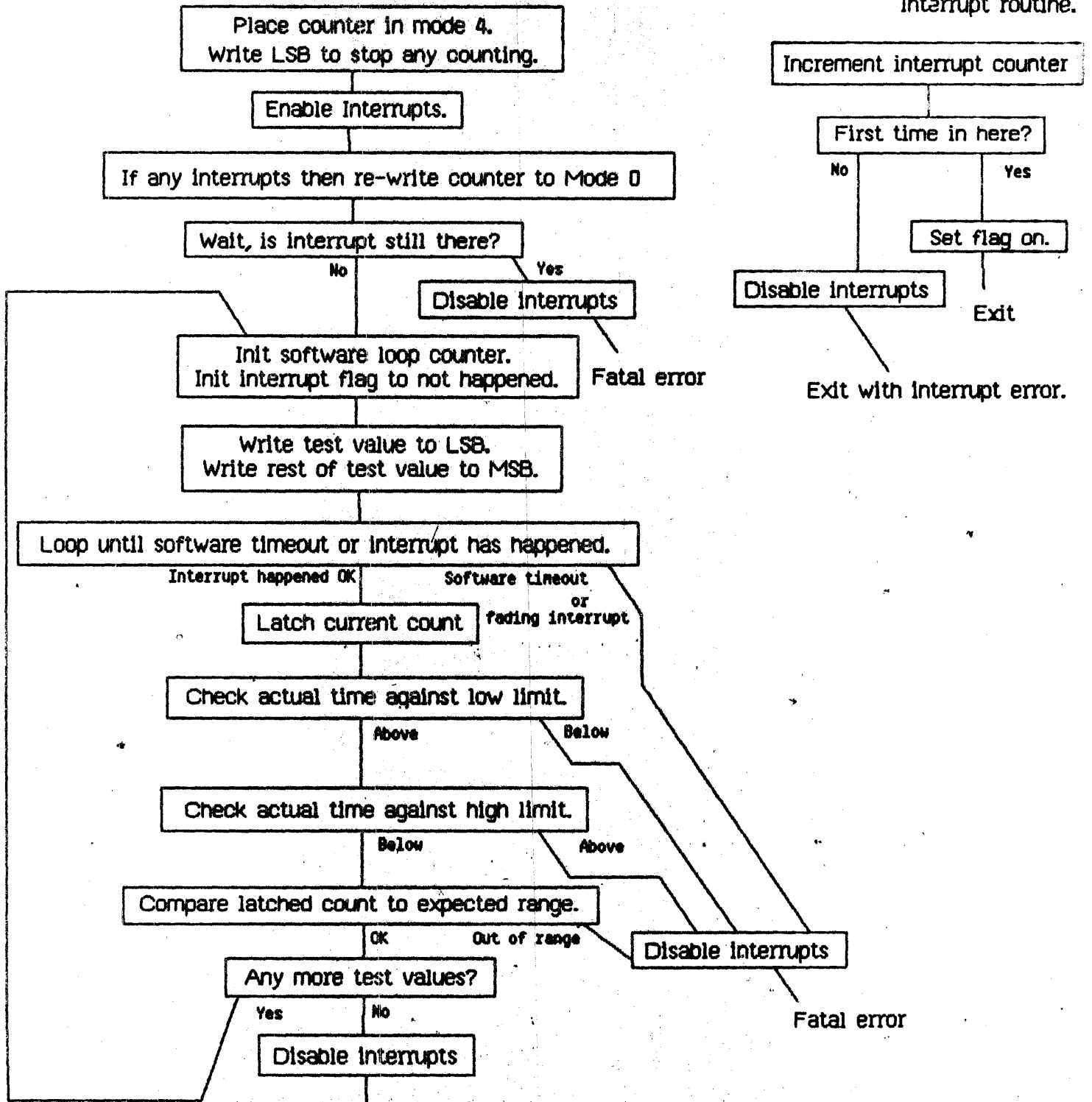
# Mode 3 test.

(3) Square wave rate generator

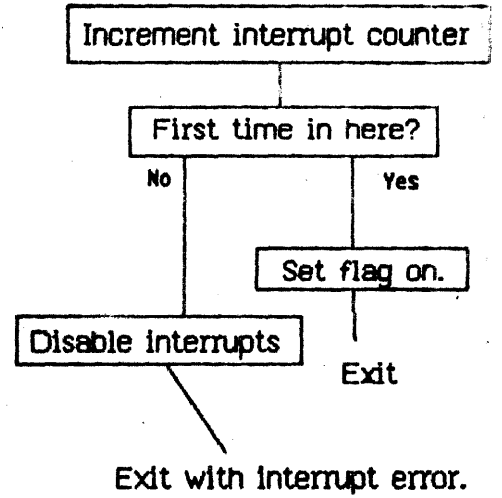


# Mode 4 test

(4) Software Triggered Strobe

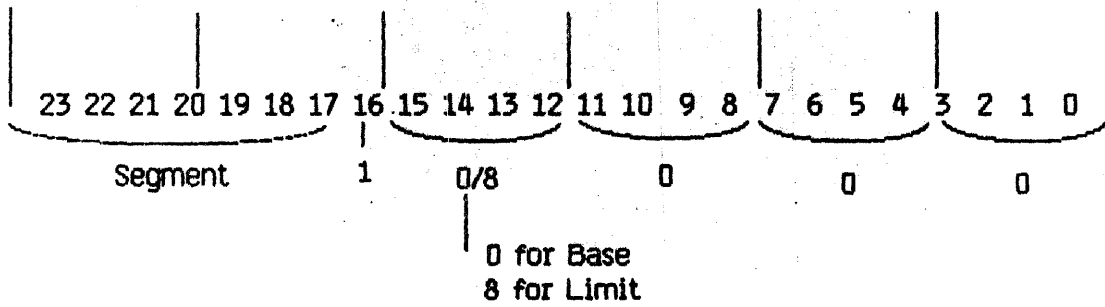


Interrupt routine.

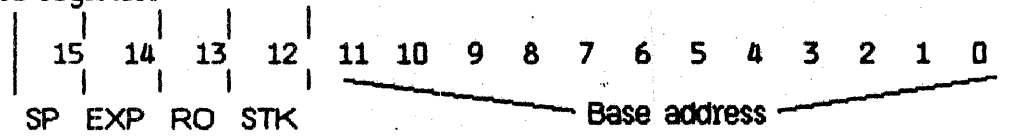


# MMU Basics

## Accessing MMU registers

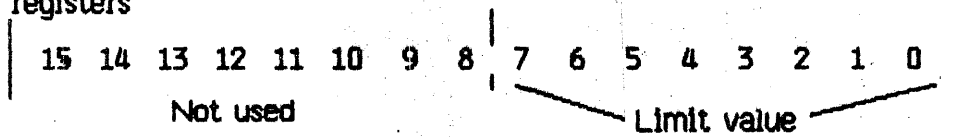


## Base registers



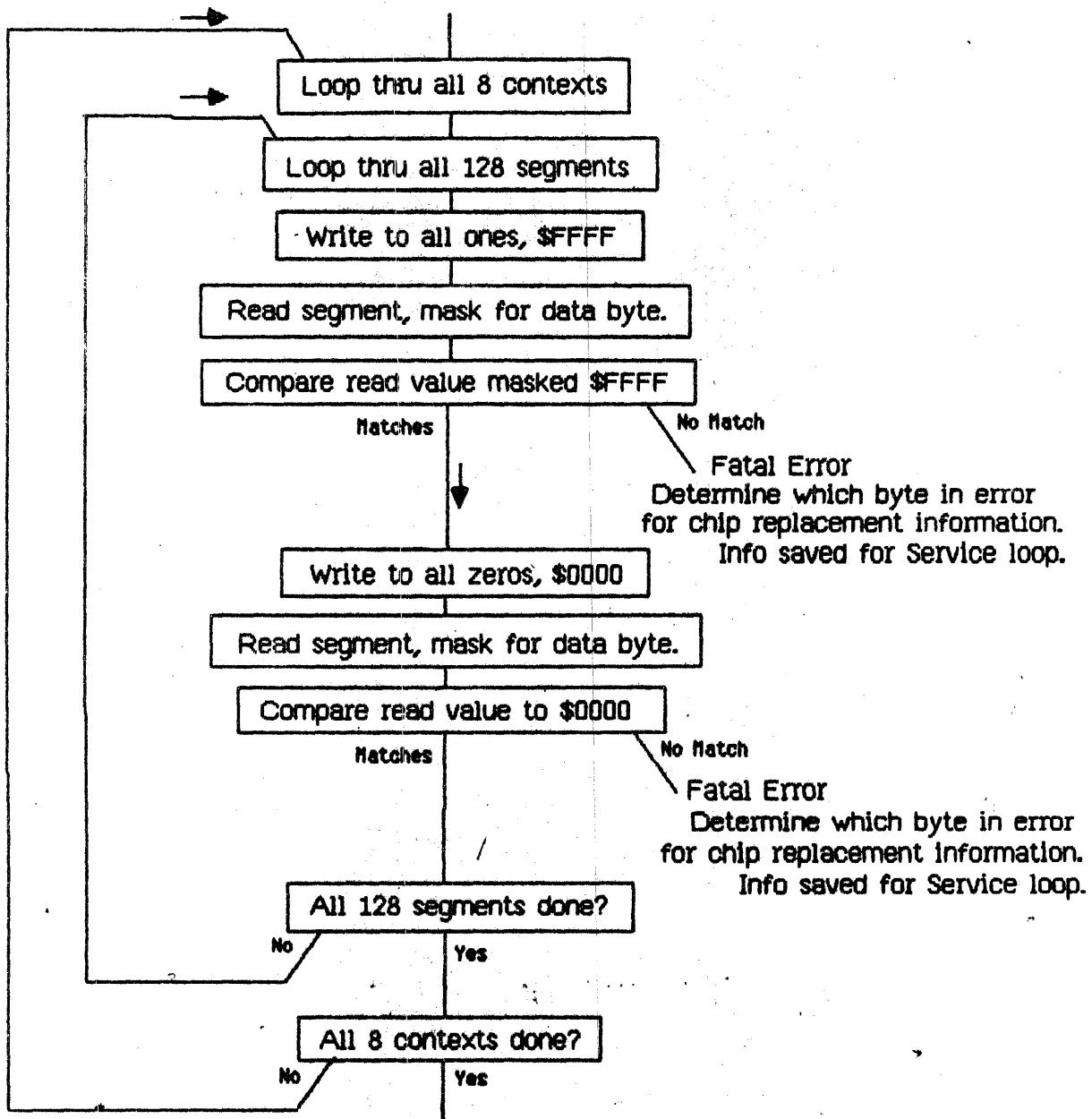
Data mask of \$FFFF is used.

## Limit registers

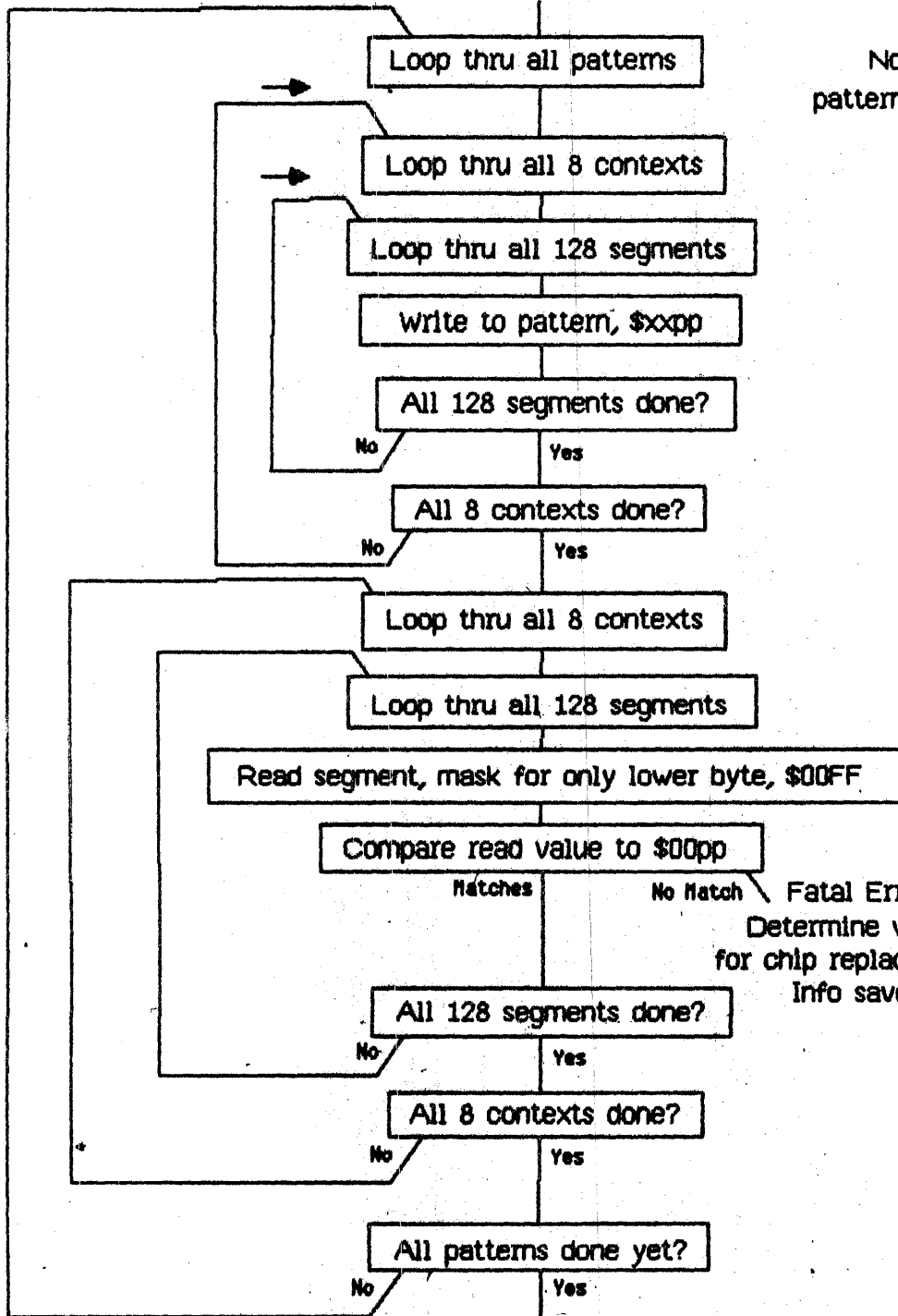


Data mask of \$00FF is used.

Stuck-at tests.



Read/Write tests.

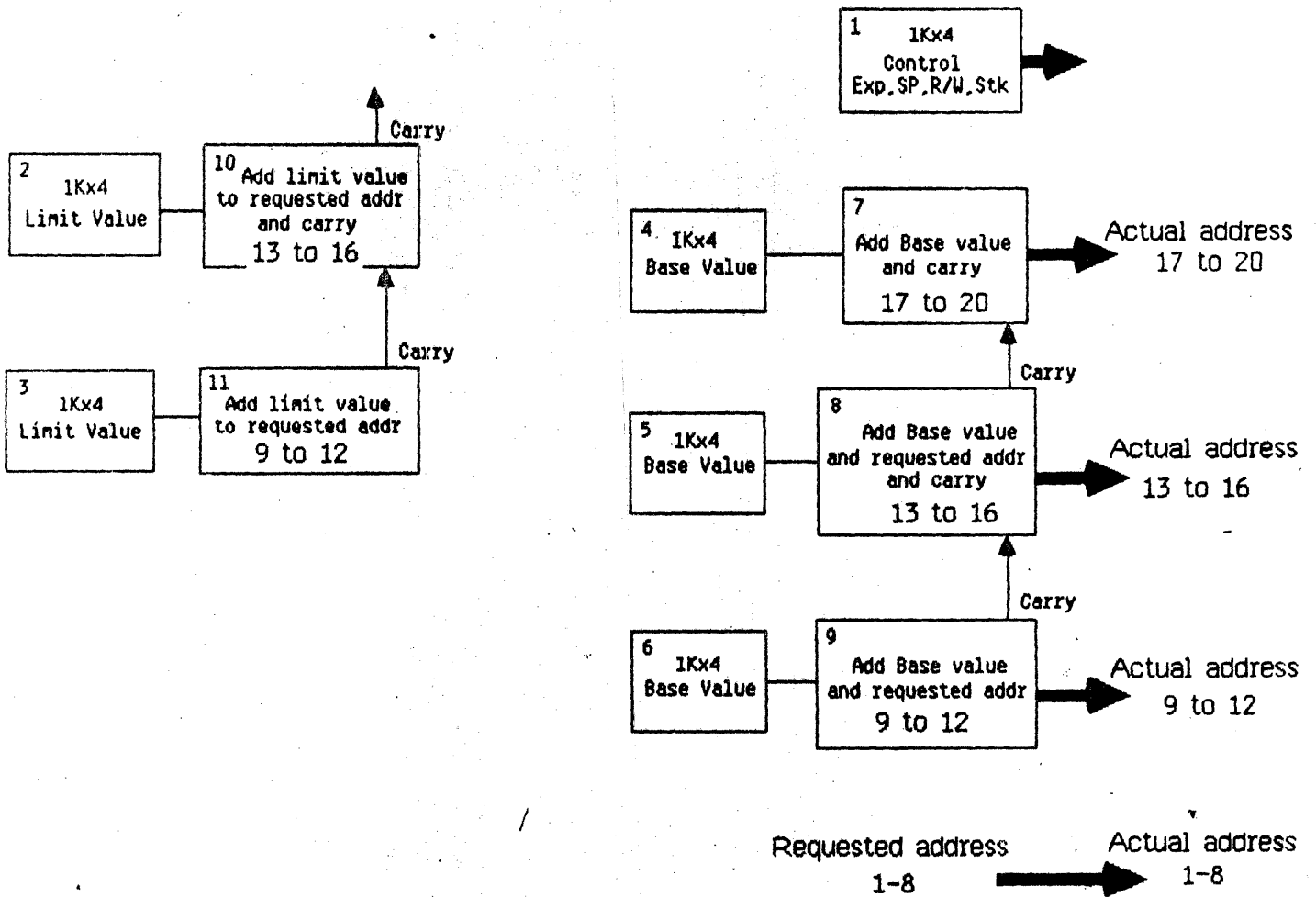


Note: One of the patterns is an address.

Fatal Error  
Determine which byte in error  
for chip replacement information.  
Info saved for Service loop.



# MMU Structure



1 to 6 tested by Ram tests.

Failure is either 1Kx4 RAM, LS245 transceiver, or LS373 xxxx.

Displayed error will show RAM, LS245, and then LS373 (In that order).

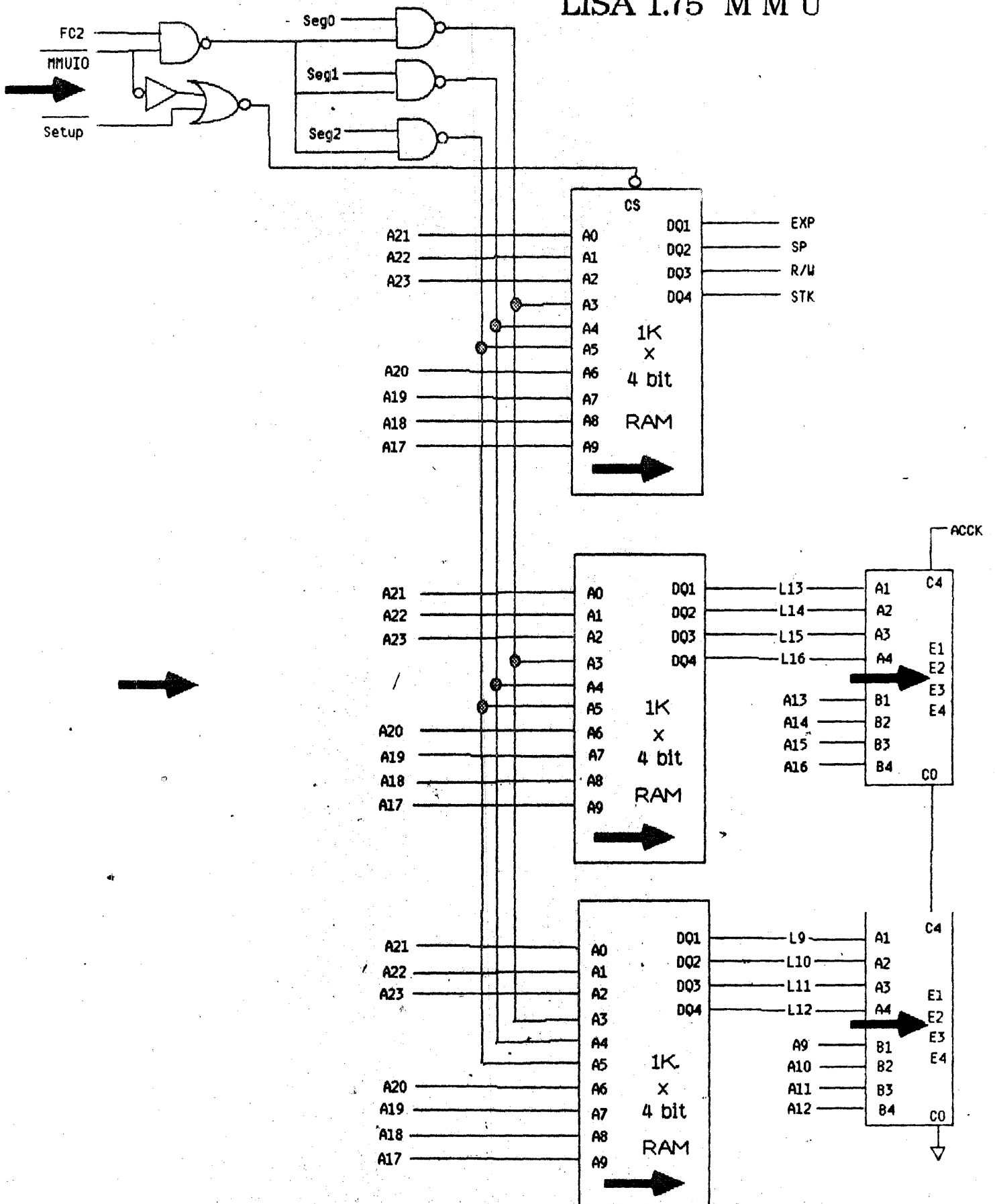
7 to 9 tested by functional tests, addresses actually accessed must agree with those expected.

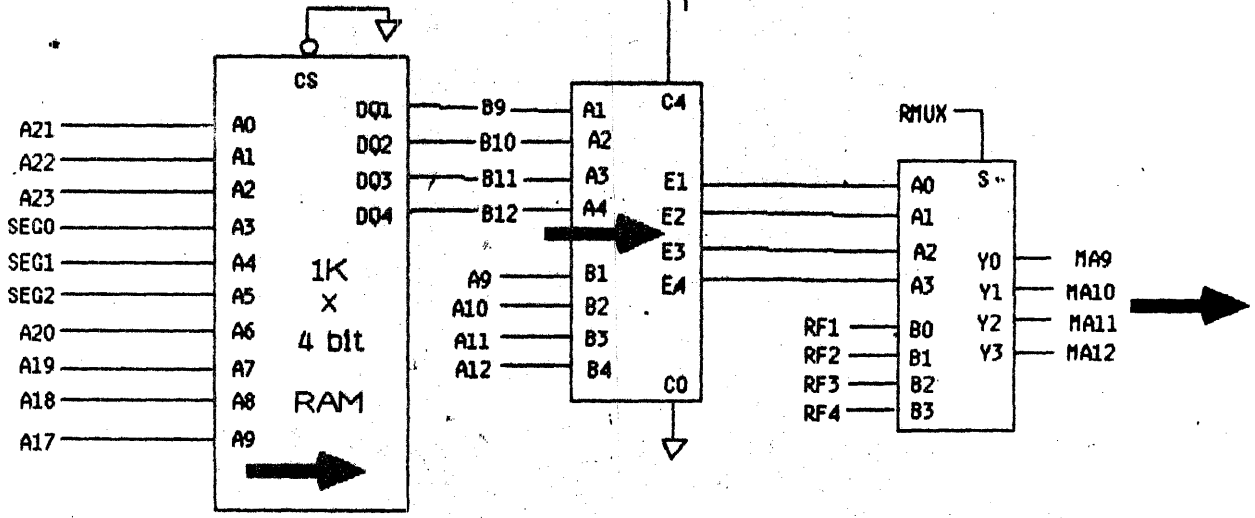
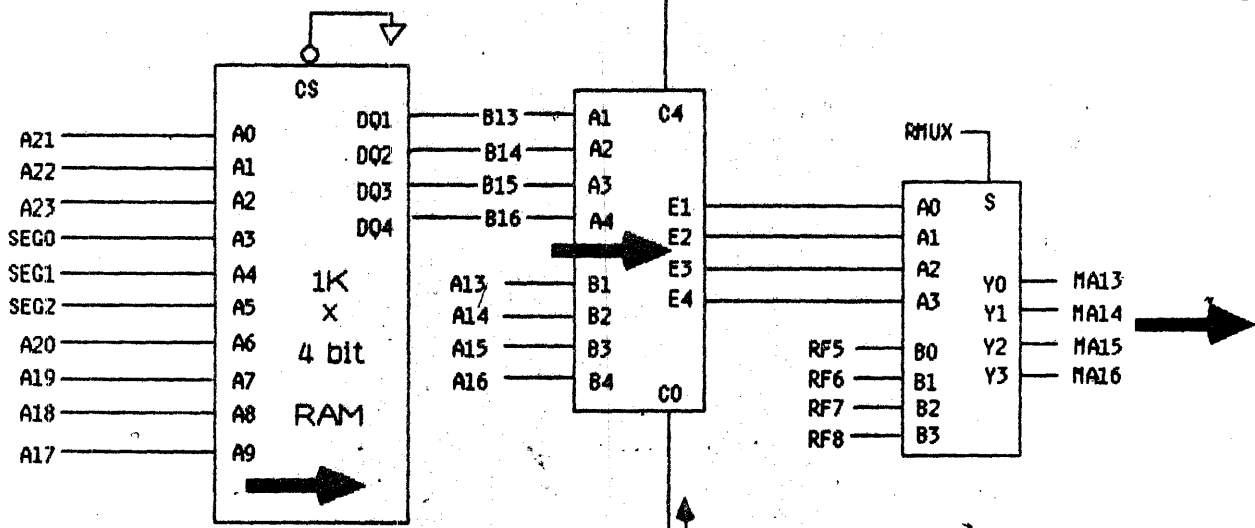
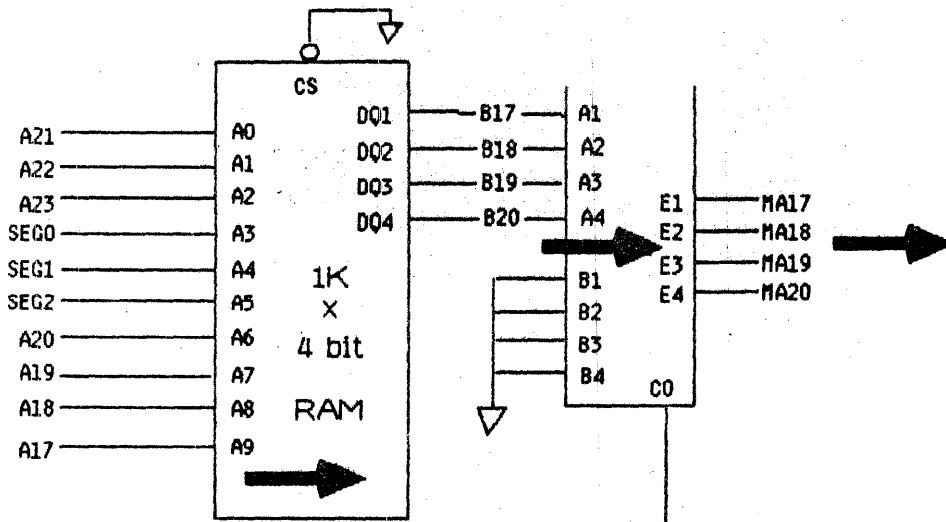
The failure will display the 283 Adder.

10 to 11 by functional tests, limit failures and legal values are both used to determine if the adders are working correctly.

The failure will display the 283 Adder.

# LISA 1.75 M M U





Edit date: 08/04/83

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MMU REGISTER TEST PROGRAM

FILE NAMES:  
MMURAM.HDR.TEXT  
MMURAM.ASM.TEXT

FUNCTION:

This is a test of the MMU RAMs on the memory board for Lisa 1.75

This test is expected to run from either ROM or from LisaTest. The ROM version is a conditional assembly subset of the LisaTest version.

Tests MMU registers by doing read/write, address, and a moving inversions test. Errors are collected and written to memory for later inspection.

After initialization, any traps will be caught and all registers are saved for perusal by user. However, during the testing when the SETUP bit is on, any exceptions will cause the exception vector to be fetched from the BOOT ROM and the BOOT ROM exception routine will be executed.

LOGIC TESTED:

The following logic on the CPU board is tested:

MMU registers for contexts 0, 1, 2, and 3

The following MMU logic is not tested:

Other MMU adder and limit checking logic  
MMU context 0 segments 0, 1, 126, and 127 registers

TECH OPTIONS:

In addition to the three standard tech-mode options, this program supplies the following:

\$0010 (16):

STEP:

\$01:

ERROR CODES:

\$00: no error

HARDWARE:

CPU board.

THEORY OF TEST OPERATION:

CAUSES OF ERRORS

Most problems caught by this test will be RAM bit errors; gross problems will be caught before this test is ever run by the BOOT RAM tests; occasionally a problem may cause the program to hang or go back to the ROM - note that any exceptions which occur during testing with the SETUP bit on will cause the 68000 to fetch the exception vector from the BOOT ROM.

ORIGINATOR: George Cossey 08/04/83

MODIFIED BY:

TO BE DONE:

=====

Register usage:

d0 - Context (0 to 7)	a0 - Base address being tested
d1 - Segment in context (0 to 127)	a1 - Limit address being tested
d2 - Write data (lower & upper)	a2 -
d3 - Read data (lower & upper)	a3 -
d4 -	a4 - Parameter address, passed
d5 -	a5 - Scratch
d6 - Scratch	a6 - Scratch
d7 - Scratch	a7 - Stack

=====

.PROC MMUREG,0  
.ORG \$0800

BSTART

; Save video memory area. (LisaTest version only)  
bsr SAVEVID  
;  
; Move test into video area. (LisaTest version only)  
bsr MOVETOVID  
jmp (a4) ; Jump to VIDEOSTART in video memory

VIDEOSTART

tst \$00003E00 ; Turn on SETUP bit  
;  
; Save all of MMU RAM data. (LisaTest version only)  
lea BMMUSAVE, a4 ; Location to save MMU information  
bsr FULLMMU  
;  
lea BASE4, a5 ; Clear failed RAM flags  
clr.l d6  
move.l d6, (a5)+  
move.l d6, (a5)+  
move.l d6, (a5)+  
;  
; Pattern tests.  
a) All zeros (0's).  
clr.l d2  
bsr PATTERN  
;  
b) All ones (1's).  
move.l #\$fffffff, d2  
bsr PATTERN  
;  
c) Checkerboard.  
move.l #\$AAAA5555, d2  
bsr PATTERN  
;  
d) Inverse checkerboard.  
move.l #\$5555AAAA, d2  
bsr PATTERN  
;  
e) Address.  
bsr ADDRESS  
;  
f) Moving Inversions.  
bsr INVERSIONS  
;  
; Restore all of MMU RAM data. (LisaTest version only)  
lea BMMUSAVE, a4 ; Location to save MMU information  
bsr RESTOREMMU  
;  
; Move back to main memory. (LisaTest version only)  
jmp JUMPBACK

JUMPBACK

tst \$00003F00 ; Turn off SETUP bit  
;  
; Restore video memory area. (LisaTest version only)  
bsr VIDRESTORE  
;  
rts

; Save video memory before test is moved up there

SAVEVID

lea BSTART, a3 ; Start of test  
lea BEND, a4 ; end of test  
lea BSAVE, a5 ; Area to save test in  
move.l \$00000800, a6 ; Video memory test area  
;  
@1 move.l (a6)+, (a5)+ ; Move from video to save area  
adda #4, a3 ; keep track of size  
cmp.l a4, a3 ; done all of test?  
bmi @1 ; ...no  
rts

; Move test to video memory, exits with transfer address in A4

MOVETOVID

lea BEND, a4  
lea BSTART, a5 ; Start of test  
move.l \$00000800, a6 ; Video memory test area  
;  
@1 move.l (a5)+, (a6)+ ; Move from main memory to video memory  
cmp.l a4, a5 ; done all of test?

```

bmi    @1                ;...no
;
lea    VIDEOSTART,a4    ;Location of where to branch to
lea    BSTART,a5        ;Start of test
suba   a5,a4            ;(VIDEOSTART - BSTART)
adda   #$00000800,a4   ;+ (Start in video memory)
rts
;
; Save all of MMU RAM data to area pointed to by A4
;
FULLMMU
; Set context, 0 to 7
clr.w  d0                ;Context
@1 bsr  SetContext
clr.w  d1                ;Segment
@2 bsr  SetSegment
move.b (a1),(a4)+       ;Read and save Limit register value
move.w (a0),(a4)+       ;Read and save Base register value
add.w  #1,d1             ;Next segment
cmp.w  #128,d1          ;..done all?
bne    @2
add.w  #1,d0             ;Next context
cmp.w  #8,d0            ;..done all?
bne    @1
rts
;
; Restore all of MMU RAM data from area at A4 (in FULLMMU saved format)
;
RESTOREMMU
; Set context, 0 to 7
clr.w  d0                ;Context
@1 bsr  SetContext
clr.w  d1                ;Segment
@2 bsr  SetSegment
move.b (a1)+,(a3)       ;Restore Limit register value
move.w (a0)+,(a5)       ;Restore Base register value
add.w  #1,d1             ;Next segment
cmp.w  #128,d1          ;..done all?
bne    @2
add.w  #1,d0             ;Next context
cmp.w  #8,d0            ;..done all?
bne    @1
rts
;
; Save video memory before test is moved up there
;
VIDRESTORE
lea    BSTART,a3        ;Start of test
lea    BEND,a4          ;end of test
lea    BSAVE,a5         ;Area to restore from
move.l $00000800,a6    ;Video memory test area
;
@1 move.l (a5)+,(a6)+    ;Move from save/area to video
adda   #4,a3            ;keep track of size
cmp.l  a4,a3            ;done all of test?
bmi    @1                ;...no
rts
;
; Pattern to write comes in inside of word d2.
; This pattern is written alternating to each ram location.
;
PATTERN
; Loop thru all contexts and segments and write test pattern
bsr    WPAT
;
; Loop thru all contexts and segments, read and compare data.
clr.w  d0                ;Context
@1 bsr  SetContext
clr.w  d1                ;Segment
@2 bsr  SetSegment
move.b (a1),d3          ;Read Limit register
cmp.b  d2,d3            ;...same as written?
beq    @3                ;...yes, continue
bsr    BADLIMIT         ;...no, flag failure
;
@3 move.w (a0),d3        ;Read Base register
cmp.w  d2,d3            ;...same as written?
beq    @4                ;...yes, continue
bsr    BADBASE          ;...no, flag failure
;
@4 add.w  #1,d1          ;Next segment
swap  d2
bsr   SetSegment
move.b (a1),d3          ;Read Limit register
cmp.b  d2,d3            ;...same as written?
beq    @5                ;...yes, continue
bsr    BADLIMIT         ;...no, flag failure
;
@5 move.w (a0),d3        ;Read Base register
cmp.w  d2,d3            ;...same as written?
beq    @6                ;...yes, continue
bsr    BADBASE          ;...no, flag failure

```



```

add.w  #0101, d2      ;Next address
move.w d2, (a0)       ;Write to Base register
add.w  #0101, d2      ;Next address
sub.w  #1, d1         ;Next segment
bpl    @12
sub.w  #1, d0         ;Next context
bpl    @11

```

```

; Loop thru all contexts and segments, read and compare data.
cir.l  d2             ;Address pattern
move.w #7, d0        ;Context
@13 bsr  SetContext
move.w #127, d1      ;Segment
@14 bsr  SetSegment
move.b (a1), d3      ;Read Limit register
cmp.b  d2, d3        ;...same as written?
beq    @15           ;...yes, continue
bsr    BADLIMIT      ;...no, flag failure
;
@15 add.w #0101, d2   ;Next address
move.w (a0), d3      ;Read Base register
cmp.w  d2, d3        ;...same as written?
beq    @16           ;...yes, continue
bsr    BADBASE       ;...no, flag failure
;
@16 add.w #0101, d2   ;Next address
sub.w  #1, d1        ;Next segment
bpl    @14
sub.w  #1, d0        ;Next context
bpl    @13
rts

```

Moving Inversions test.

Example:

- Low to high pass
1. Write background pattern
  2. For every (1) addr, low to high, do Read/Verify, Write complement, Read/Verify
  3. Two (2) passes, for every other address (first even, second odd) do Read/Verify, Write complement, Read/Verify
  4. Four (4) passes, for every 4th address (first even, second odd,...) do Read/Verify, Write complement, Read/Verify
  5. Eight (8) passes, for every 8th address (first even, second odd,...) do Read/Verify, Write complement, Read/Verify
  6. .... until step count equals one half the size of the memory.

- High to low pass
1. Write background pattern
  2. For every (1) addr, high to low, do Read/Verify, Write complement, Read/Verify
  3. Two (2) passes, for every other address (first even, second odd) do Read/Verify, Write complement, Read/Verify
  4. Four (4) passes, for every 4th address (first even, second odd,...) do Read/Verify, Write complement, Read/Verify
  5. Eight (8) passes, for every 8th address (first even, second odd,...) do Read/Verify, Write complement, Read/Verify
  6. .... until step count equals one half the size of the memory.

Step	(1)	(2)	(4)
Pass	1	1 2	1 2 3 4
Lac	0 xx	xx	xx
	1 xx	xx	xx
	2 xx	xx	xx
	3 xx	xx	xx
	4 xx	xx	xx
	5 xx	xx	xx
	6 xx	xx	xx
	7 xx	xx	xx
	8 xx	xx	xx
	9 xx	xx	xx
	10 xx	xx	xx
	11 xx	xx	xx

Total passes = 10 for 1K RAM,  
 Increments: 1, 2, 4, 8, 16, 32, 64, 128, 256, 512

Increment = x  
 Passes = x  
 Expect = \$FOFO All ones and all zeros for each 1Kx4 RAM  
 Compl Exp = \$FOFO

Write all of MMU to \$FOFO

Total Pass Loop

Pass loop  
 Read data.  
 Compare to expect and log failures.







; Sets to requested context, number 0 to 7 in d0

```
SETCONTEXT
and.w    #$7, d0      ; Make it legal
;
tst.w    $0003800     ; SEGO to a 0
tst.w    $0003A00     ; SEG1 to a 0
tst.w    $0003C00     ; SEG2 to a 0
;
cmp.w    #0, d0
bne     @1
bra     @10
;
@1 cmp.w    #1, d0
bne     @2
tst.w    $0003900     ; SEGO to a 1
bra     @10
;
@2 cmp.w    #2, d0
bne     @3
tst.w    $0003B00     ; SEG1 to a 1
bra     @10
;
@3 cmp.w    #3, d0
bne     @4
tst.w    $0003900     ; SEGO to a 1
tst.w    $0003B00     ; SEG1 to a 1
bra     @10
;
@4 tst.w    $0003D00     ; SEG2 to a 1
cmp.w    #4, d0
bne     @5
bra     @10
;
@5 cmp.w    #5, d0
bne     @6
tst.w    $0003900     ; SEGO to a 1
bra     @10
;
@6 cmp.w    #6, d0
bne     @6
tst.w    $0003B00     ; SEG1 to a 1
bra     @10
;
@7 tst.w    $0003900     ; SEGO to a 1
tst.w    $0003B00     ; SEG1 to a 1
;
@10 rts
```

; Sets segment address for Limit register in a3, segment requested in d1.  
; Uses d5 as scratch

```
SetSegment
move.l   #$010000, a1 ; Address of first Limit register
move.w   d1, d5
and.l   #$7F, d5      ; Make legal
swap    d5            ; Now in bits 15 to 21
asl.l   #2, d5        ; Now in bits 17 to 23
adda    d5, a1        ; Final address
move.l   a1, d5
or.l    #$008000, d5
move.l   d5, a0
rts
```

; Get address based on d7  
; Returns addresses in a0 and a1

```
GetAddress
clr.l   d6            ; Current counter
clr.w   d0            ; Context
@1 bsr    SetContext
clr.w   d1            ; Segment
@2 bsr    SetSegment
cmp.w   d6, d7        ; At requested?
beq     @3
add.w   #1, d6
add.w   #1, d1        ; Next segment
cmp.w   #128, d1      ; ..done all?
bne     @2
add.w   #1, d0        ; Next context
cmp.w   #8, d0        ; ..done all?
bne     @1
@3 rts
```

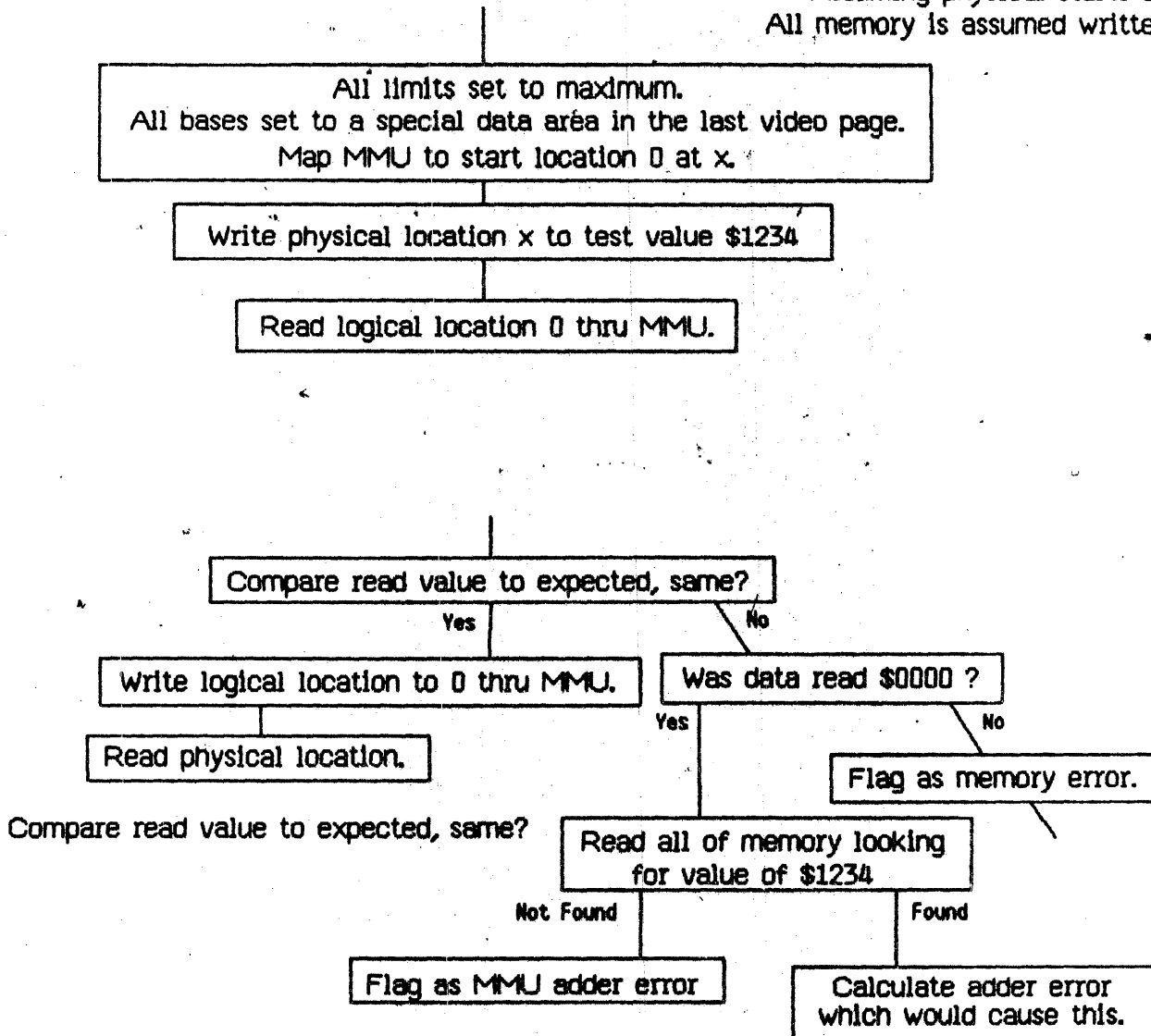
; Table of bad RAMs, 0 means good, other means failure  
; (Table must be grouped for clear to work properly)

```
BASE4 .WORD 0 ; Base register bits 12-15
BASE3 .WORD 0 ; Base register bits 8-11
BASE2 .WORD 0 ; Base register bits 4-7
BASE1 .WORD 0 ; Base register bits 0-3
LIMIT2 .WORD 0 ; Base register bits 4-7
LIMIT1 .WORD 0 ; Base register bits 0-3
```

```
;
BMMUSAVE ; The data following is the current state of the MMU before the test
;
BEND ; This is the end of the test that is copied to video memory
;
BSAVE ; This is the start of the saved video memory area.
;
.END
```

# MMU Functional

Assuming physical starts at x.  
All memory is assumed written to 0.



Data area in last video page is set to a specific pattern.

The data area pattern is read thru all segment addresses.

# Base address adders.

	Base	Physical
Sum 4, COut	\$00080000	\$00000000
	\$00070001	\$0000FFFF
	\$000F0001	\$0000FFFF

Sum 3	\$00040000	\$00000000
	\$00030001	\$0000FFFF
	\$00070001	\$0000FFFF

Sum 2	\$00020000	\$00000000
	\$00010001	\$0000FFFF
	\$00030001	\$0000FFFF

Sum 1	\$00010000	\$00000000
	\$00000001	\$0000FFFF
	\$00010001	\$0000FFFF

	Base	Physical
Sum 4, COut	\$00008000	\$00000000
	\$00000000	\$00008000
	\$00008000	\$00008000

Sum 3	\$00004000	\$00000000
	\$00000000	\$00004000
	\$00004000	\$00004000

Sum 2	\$00002000	\$00000000
	\$00000000	\$00002000
	\$00002000	\$00002000

Sum 1	\$00001000	\$00000000
	\$00000000	\$00001000
	\$00001000	\$00001000

	Base	Physical
Sum 4, COut	\$00000800	\$00000000
	\$00000000	\$00000800
	\$00000800	\$00000800

Sum 3	\$00000400	\$00000000
	\$00000000	\$00000400
	\$00000400	\$00000400

Sum 2	\$00000200	\$00000000
	\$00000000	\$00000200
	\$00000200	\$00000200

Sum 1	\$00000000	\$00000000
	\$00000100	\$00000000
	\$00000000	\$00000100
	\$00000100	\$00000100

FILE NAMES:  
TWOP.HDR.TEXT  
TWOP.ASM.TEXT  
TWOPORT (code file)

FUNCTION:  
Verify as much of the Two Port Card as possible.

LOGIC TESTED:  
Portions of the Two Port Card, as described below.

TECH OPTIONS:  
The following options are supported (1-3 are standard):

- 0: normal program execution
- 1: loop until NMI (error count kept in ERRCNT, loop count in OUTCNT)
- 2: loop INCNT number of times (or until error)(loop count in OUTCNT)
- 3: loop on test until error (loop count kept in OUTCNT),  
exit test at error without resetting cause of error
  
- 10: Loop on sending data thru PA0-PA7 from port A to port B
- 11: Loop on sending data thru PA0-PA7 from port B to port A
- 12: Loop on sending from PB7(CRES) to PB0(OCD) from port A to port B
- 13: Loop on sending from PB7(CRES) to PB0(OCD) from port B to port A
- 14: Loop on sending from PB4(CMD) to PB6(PARITY) from port A to port B
- 15: Loop on sending from PB4(CMD) to PB6(PARITY) from port B to port A
- 16: Loop on sending from PB3(R/W) to CB1(CHK) from port A to port B
- 17: Loop on sending from PB3(R/W) to CB1(CHK) from port B to port A
- 18: Loop on sending from CA2(STRB) to PB1/CA1(BSY) from port A to port B
- 19: Loop on sending from CA2(STRB) to PB1/CA1(BSY) from port B to port A
- 20: Loop on sending from port B to test Port A parity circuit.
- 21: Loop on sending from port A to test Port B parity circuit.
  
- 32: Loop at end of test, for program debug use.
- 33: Ignore any timer test failures, gather data for debug use.

ERROR CODES:

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Step:

- 1 - Initial test setup, hardware and software.
- 2 - Check data lines to Two Port Card.
- 3 - Check interrupt capability of Two Port Card.
- 4 - Port A 6522(VIA) register test.
- 5 - Port B 6522(VIA) register test.
- 6 - Port A 6522(VIA), Timer #1 test.
- 7 - Port A 6522(VIA), Timer #2 test.
- 8 - Port B 6522(VIA), Timer #1 test.
- 9 - Port B 6522(VIA), Timer #2 test.
- 10 - PA0-PA7 data lines thru loopback connector test, both ports.
- 11 - PB0,PB7 data lines thru loopback connector test, both ports.
- 12 - PB4,PB6 data lines thru loopback connector test, both ports.
- 13 - PB3,CB1 data lines thru loopback connector test, both ports.
- 14 - CA2,PB1 data lines thru loopback connector test, both ports.
- 15 - Port A Parity circuit test.
- 16 - Port B Parity circuit test.

Errors:

- 0 - no error
- 1 - Could not locate Two Port Card in any expansion slot.
- 2 - Data read is not the same as data written to register on VIA.
- 3 - Card could not supply an interrupt (possibly timer #1 also).
- 4 - 6522(VIA) Timer failure. Timer too fast, time is too short.
- 5 - 6522(VIA) Timer failure. Timer too slow, time is too fast.
- 6 - Data line PA0-PA7 failed wraparound test, port A driving port B,  
or no Loop-Back connector installed.
- 7 - Data line PA0-PA7 failed wraparound test, port B driving port A.
- 8 - OCD(PB0) or RESET/(PB7) failed, port A driving port B.
- 9 - OCD(PB0) or RESET/(PB7) failed, port B driving port A.
- 10 - CMD(PB4) or PARITY(PB6) failed, port A driving port B.
- 11 - CMD(PB4) or PARITY(PB6) failed, port B driving port A.
- 12 - Interrupt occurred when none expected, on Port A.
- 13 - Interrupt occurred when none expected, on Port B.
- 14 - Expected interrupt did not occur on port B.
- 15 - Expected interrupt did not occur on port A.
- 16 - STRB(CA2) or BSY(PB1) failed, port A driving port B.
- 17 - STRB(CA2) or BSY(PB1) failed, port B driving port A.
- 18 - PB1 on port B failure (BSY), port A driving port B.
- 19 - PB1 on port A failure (BSY), port A driving port B.
- 20 - Bad data (PA0-PA7) during parity test of Port A.
- 21 - Parity circuit for port A gives wrong summation result (CB2).
- 22 - Bad data (PA0-PA7) during parity test of Port A.
- 23 - Parity circuit for port A gives wrong summation result (CB2).

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HARDWARE: Working LISA, I/O Port Test Card (cables connected or not).

THEORY OF TEST OPERATION:

Register Read/Write test of the VIA (6522). This test verifies that most if the registers in the 6522 are read/write-able. This test does not test all registers since some registers are read or write only.

Details:

a) All registers are initialized as follows.

Timer test for the 6522. Timer #1 and Timer #2 are tested to assure that interrupts are generated at the end of the programmed time.

WRITTEN BY: REV 1.0 G.Cossey 01/21/83

MODIFIED: REV 1.1 G.Cossey 04/12/83, now uses library routines. Removed code to run on APPLE II, now only from LISA.

TO BE DONE:

```

=====
. ABSOLUTE
.PROC TWOPORT,0
;
=====
; TRAP AND ERROR VECTOR LOCATIONS
=====
BUSVCT .EQU $0008 ; bus error
ADRVCT .EQU $000C ; address error
ILLVCT .EQU $0010 ; illegal instruction
AXXVCT .EQU $0028 ; future traps (emulator)
FXXVCT .EQU $002C
;
=====
; INTERNAL INTERRUPT VECTORS
=====
LEV1VCT .EQU $0064 ; floppy, parallel port, VTIR
LEV2VCT .EQU $0068 ; keyboard interface VIA
LEV3VCT .EQU $006C ; slot 2
LEV4VCT .EQU $0070 ; slot 1
LEV5VCT .EQU $0074 ; slot 0
LEV6VCT .EQU $0078 ; RS232 chip
NMIVCT .EQU $007C ; NMI
;
=====
; now, the local equates . . .
=====
ORB equ $00 ; port B
ORA equ $08 ; port A
DDRB equ $10 ; Data direction of port B
DDRA equ $18 ; port A
T1CL equ $20 ; T1 Counter (low)
T1CH equ $28 ; (high)
T1LL equ $30 ; T1 Latch (low)
T1LH equ $38 ; (high)
T2CL equ $40 ; T2 Counter
T2CH equ $48
SHR equ $50 ; Shift register
ACR equ $58 ; Aux control
PCR equ $60 ; Peripheral control
IFR equ $68 ; Int. flags
IER equ $70 ; interrupt enable
;
; For Keyboard COPS use.
KBOVIA equ $fcdd80 ; Base address for keyboard VIA 6522
KIER equ 29 ; interrupt enable
;
=====
; START - PROGRAM ENTRY POINT
=====
.ORG $0800 ; we are normally loaded at $800 (we try to be
; relocatable, though)
START BRA S START1 ; skip around parameter area
;
REVDATE .WORD 11,0 ; Revision number (use decimal numbers for Pascal)
; ... x.x > xx, so REV 1.0 is 10 here.
; label "TECH" is location START +6 ($806)
; note - parameters are word-length (2 bytes)
TECH .WORD 0 ; non-zero values select tech-mode options
; the next three parameter words are used only
; if the tech mode is non-zero.
;
ERRCNT .WORD 0 ; exit parm - holds number of errors encountered
OUTCNT .WORD 0 ; exit parm - holds number of passes completed
INCNT .WORD 0 ; entry parm - holds number of times to execute prog
RESVD .WORD 0 ; reserved for later expansion
;
IERRCNT .EQU 2
IOUTCNT .EQU 4
IINCNT .EQU 6

```



```

;
; =====;
; INPUT PARAMETERS - START + $010
; =====;
INBUF0 .WORD 0 ; currently unused
INBUF1 .WORD 0
INBUF2 .WORD 0
INBUF3 .WORD 0
INBUF4 .WORD 0
INBUF5 .WORD 0
INBUF6 .WORD 0
INBUF7 .WORD 0
; =====;
; RESULT BUFFER - START + $020
; =====;
DREGS .WORD 0,0 ; (D0) :
      .WORD 0,0 ; (D1) :
      .WORD 0,0 ; (D2) :
      .WORD 0,0 ; (D3) :
      .WORD 0,0 ; (D4) :
      .WORD 0,0 ; (D5) :
      .WORD 0,0 ; (D6) : step number
      .WORD 0,0 ; (D7) : error code
;
AREGS - START + $040
AREGS .WORD 0,0 ; (A0) :
      .WORD 0,0 ; (A1) :
      .WORD 0,0 ; (A2) :
      .WORD 0,0 ; (A3) :
      .WORD 0,0 ; (A4) :
      .WORD 0,0 ; (A5) :
      .WORD 0,0 ; (A6) : obliterated restoring environment
      .WORD 0,0 ; (A7) : stack pointer
;
EXCEPTION INFO - START + $060
; GROUP 0
EXCFC .WORD 0 ; function code
EXCADR .WORD 0,0 ; address
EXCIR .WORD 0 ; instruction register
; GROUP(=) 0 & 1
EXCSR .WORD 0 ; status register
EXCPC .WORD 0,0 ; program counter
OLDPC .WORD 0,0
OLDSP .WORD 0,0
OLDSR .WORD 0,0
;
; =====;
; NOW CONTINUE WITH THE CODE
; =====;
START1 LEA OLDP, A0 ;
      MOVE.L (SP)+, (A0) ; save return address, set SP to top of
      LEA OLDSR, A0 ; new stack
      MOVE.L SP, (A0) ; then save it also
      LEA START, SP ; place our stack right below the program
;
      LEA OLDSR, A0 ; Save status reg value
      MOVE.L SR, (A0)
      ORI.W #$0700, SR ; Disable interrupts
;
      LEA MISC, A0 ; initialize interrupt and trap vectors in case
      MOVEA #0, A1 ; of unexpected exceptions
      LEA OLDVCTR, A2 ; also save incoming vectors
      MOVEQ #64, D0
@1 MOVE.L (A1), (A2)+ ; save incoming vectors in array OLDVCTR
      MOVE.L A0, (A1)+ ; first set all vectors to point to miscellaneous
      SUBQ #1, D0 ; exception handler . . .
      BGT @1
;
      LEA BUSERR, A0 ; then set up special vectors for the more
      MOVE.L A0, BUSVCT ; common exceptions . . .
      LEA ADRERR, A0
      MOVE.L A0, ADRVCT
      LEA ILLERR, A0
      MOVE.L A0, ILLVCT
      LEA LEV1INT, A0
      MOVE.L A0, LEV1VCT
      LEA LEV2INT, A0
      MOVE.L A0, LEV2VCT
      LEA LEV3INT, A0
      MOVE.L A0, LEV3VCT
      LEA LEV4INT, A0
      MOVE.L A0, LEV4VCT
      LEA LEV5INT, A0
      MOVE.L A0, LEV5VCT
      LEA LEV6INT, A0
      MOVE.L A0, LEV6VCT
      LEA NMI, A0
      MOVE.L A0, NMIVCT
;
      CLR.L D0 ; clear all the registers except A7
      CLR.L D1
      CLR.L D2
      CLR.L D3
      CLR.L D4

```

```

CLR.L D5
CLR.L D6
CLR.L D7
MOVEA.L D0, A0
MOVEA.L D0, A1
MOVEA.L D0, A2
MOVEA.L D0, A3
MOVEA.L D0, A4
MOVEA.L D0, A5
MOVEA.L D0, A6
BRA MAIN ; and branch to the main routine
;
; =====;
; DEFAULT EXCEPTION HANDLERS ; these exception handlers just set an error
; =====; ; code and exit . . .
MISC MOVEQ #50, D7 ; miscellaneous exceptions (traps, divide by 0,
BRA.S EXCP ; etc.)
BUSERR MOVEQ #51, D7 ; bus error exception (bus timeout, invalid MMU
BRA.S EXCP0 ; access)
ADRERR MOVEQ #52, D7 ; address error
BRA.S EXCP0
ILLERR MOVEQ #53, D7 ; illegal instruction error
BRA.S EXCP
;
LEV1INT MOVEQ #571, D7 ; level 1 interrupt (parallel port, vertical
BRA.S EXCP ; retrace)
LEV2INT MOVEQ #572, D7 ; level 2 interrupt (keyboard)
BRA.S EXCP
LEV3INT MOVEQ #573, D7 ; level 3 interrupt (expansion slot 2)
BRA.S EXCP
LEV4INT MOVEQ #574, D7 ; level 4 interrupt (expansion slot 1)
BRA.S EXCP
LEV5INT MOVEQ #575, D7 ; level 5 interrupt (expansion slot 0)
BRA.S EXCP
LEV6INT MOVEQ #576, D7 ; level 6 interrupt (RS-232 ports)
BRA.S EXCP
NMI MOVEQ #577, D7 ; level 7 (NMI) interrupt (parity error)
BRA.S EXCP
;
EXCP0 LEA EXCFC, A6 ; NOTE A6 IS DESTROYED HERE
MOVE (SP)+, (A6)+ ; save extra info for group 0
MOVE.L (SP)+, (A6)+
MOVE (SP)+, (A6)+
EXCP LEA EXCSR, A6
MOVE (SP)+, (A6)+ ; save common exception info
MOVE.L (SP)+, (A6)+
;
; EXIT. Save current register contents in save area and return to caller
;
EXIT
ORI.W #0700, SR ; disable interrupts
LEA DREGS, A6
MOVEM.L D0-D7/A0-A7, (A6) ; push return registers in result buffer
;
LEA OLDVCTR, A0 ; restore incoming exception vectors
MOVEA #0, A1
MOVEQ #64, D0
@1 MOVE.L (A0)+, (A1)+
SUBQ #1, D0
BGT.S @1
;
LEA OLDSR, A0 ; Restore incoming status register
MOVE.L (A0), SR
;
LEA OLDSP, A6 ; get back incoming stack pointer
MOVE.L (A6), SP
LEA OLDFC, A6 ; and program counter
MOVE.L (A6), -(SP)
RTS
;
OLDVCTR .BLOCK 256, 0 ; storage area for incoming exception vectors
;
.INCLUDE lib: COPSCMD.TEXT
.INCLUDE lib: FINDC.ASM.TEXT
.INCLUDE TWOP.ASM.TEXT
;
.END

```

```

; Edit Date: 04/12/83
;-----
; File: TWOP.ASM.TEXT
; NOTE: Refer to TWOP.HDR.TEXT for program details.
;-----

```

```

TICKTOCK equ 0 ;Timer counter
T1 equ 2 ;Timer 1 happened flag
T2 equ 4 ;Timer 2 happened flag
KBDIEN equ 6 ;Keyboard VIA interrupt enable value
SAVEVECTOR equ 8 ;Interrupt vector address, original
WhichTimer equ 12 ;Flag for timer under test
CA1VIA1 equ 14
CA1VIA2 equ 16
CB1VIA1 equ 18
CB1VIA2 equ 20
ParityTests equ 22

```

```

;-----
; a0 - Scratch d0 - Scratch
; a1 - Scratch d1 - Scratch
; a2 - First VIA address. d2 - Scratch
; a3 - Second VIA address. d3 - Scratch
; a4 - Interrupt vector address d4 - Scratch
; a5 - LOCAL variable table. d5 - Tech Mode
; a6 - DEBUG d6 - Step number
; a7 - Stack d7 - Error code
;-----

```

```

MAIN clr.w d7 ;Clear error flag
      move.w #1,d6 ;Init to step #1
      lea LOCAL,a5 ;LOCAL table pointer
      lea DEBUG,a6
      ^
      move.b #$00,d1 ;Boot ID looking for
      move.b #$02,d2
      bsr FINDC
      cmp.w #0,d0 ;...find it?
      beq @105 ;...no, exit with error

      lea INTCARD,a1
      move.l 2(a3),(a1) ;...address of interrupt vector
      move.l 2(a3),a4
      lea CARD,a1 ;Base address
      move.l 6(a3),(a1) ;...address of VIA

      move.l (a1),a2 ;First VIA /
      adda #$2001,a2
      move.l a2,(a6) ;for debug
      move.l (a1),a3 ;Second VIA
      adda #$2801,a3
      move.l a3,6(a6) ;for debug

      lea TECH,a1
      move.w (a1),d5 ;Get Tech Mode

      bsr DISABLEOTHER ;Disable interrupts from other sources
;
;@1 clr.w d7 ;Clear fail flag.
;
      cmp.w #10,d5 ;See if special tech mode loops wanted
      beq @2
      cmp.w #11,d5
      beq @2
      cmp.w #12,d5
      beq @3
      cmp.w #13,d5
      beq @3
      cmp.w #14,d5
      beq @4
      cmp.w #15,d5
      beq @4
      cmp.w #16,d5
      beq @5
      cmp.w #17,d5
      beq @5
      cmp.w #18,d5
      beq @6
      cmp.w #19,d5
      beq @6
      cmp.w #20,d5
      beq @7
      cmp.w #21,d5
      beq @8

      move.w #2,d6 ;Step #2
      bsr CHECKLINE ;Check data line connection to card.
      cmpi.w #0,d7 ;...any errors?
      bne @10 ;...exit on error

```

*Handwritten notes:*  
 KF 100  
 KF 1910

```

;
move.w #3,d6 ;Step #3
bsr CKINTERRUPT ;Check can get interrupt from TH0 Port card.
cmpi.w #0,d7 ;...any errors?
bne @10 ;...exit on error
;
move.w #4,d6 ;Step #4
bsr CK1VIA ;Check registers on first 6522(VIA)
cmpi.w #0,d7 ;...any errors?
bne @10 ;...exit on error
;
move.w #5,d6 ;Step #5
bsr CK2VIA ;Check registers on second VIA
cmpi.w #0,d7 ;...any errors?
bne @10 ;...exit on error
;
move.w #6,d6 ;Step #6,7
bsr CK1TIMER ;Check timers on 6522(VIA)
cmpi.w #0,d7 ;...any errors?
bne @10 ;...exit on error
;
move.w #8,d6 ;Step #8,9
bsr CK2TIMER ;Check timers on 6522(VIA)
cmpi.w #0,d7 ;...any errors?
bne @10
;
@2 move.w #10,d6 ;Step #10
bsr PA0to7 ;Check connection thru cable, PA0-PA7
cmpi.w #0,d7 ;...any errors?
bne @10
;
@3 move.w #11,d6 ;Step #11
bsr PB0and7 ;Check connection thru cable PB0,PB7
cmpi.w #0,d7 ;...any errors?
bne @10
;
@4 move.w #12,d6 ;Step #12
bsr PB4and6 ;Check connection thru cable PB4,PB6
cmpi.w #0,d7 ;...any errors?
bne @10
;
@5 move.w #13,d6 ;Step #13
bsr PB3andCB1 ;Check connection thru cable PB3,CB1
cmpi.w #0,d7 ;...any errors?
bne @10
;
@6 move.w #14,d6 ;Step #14
bsr CA2andPB1 ;Check connection thru cable CA2,PB1
cmpi.w #0,d7 ;...any errors?
bne @10
;
@7 move.w #15,d6 ;Step #15
bsr AParity ;Check Port A parity circuit
cmpi.w #0,d7 ;...any errors?
bne @10
;
@8 move.w #16,d6 ;Step #16
bsr BParity ;Check Port B parity circuit
cmpi.w #0,d7 ;...any errors?
bne @10
;
@10 bsr RESTORE ;Restore any disabled functions
;
lea TECH,a1
cmpi.w #0,d7 ;test for errors
bne @100 ;...toggle pass counter?
addq.w #1,IOUTCNT(a1) ;...yes, Increment pass counter.
bra @101
@100 addq.w #1,IERRCNT(a1)
@101 subq.w #1,IINCNT(a1) ;Decrement test limit counter
;
cmp.w #1,d5 ;See if Tech mode 1
beq MAIN ;...yes, loop forever
;
cmp.w #2,d5 ;See if Tech mode 2
bne @102 ;...no
cmp.w #0,d7 ;...Error occured?
bne @103 ;...yes, abort test
cmp.w #0,IINCNT(a1) ;...test count expired?
bne MAIN ;...no, continue.
;
@102 cmp.w #3,d5 ;See if Tech mode 3
bne @103 ;...no
cmp.w #0,d7 ;...Error occured?
bne @103 ;...yes, abort test
bra MAIN
;
@103 cmpi.w #320,d5 ;Tech Mode, loop at end of test?
beq @103
; Normal exit
@104 bra EXIT
;
; Error exit, could not find card
@105 move.w #1,d7
bra @104

```

```

;
;=====
; Disable interrupts from other sources
;
DISABLEOTHER  ori  #0700, sr      ; mask all interrupts
               lea   KBDVIA, a1    ; Get Keyboard VIA address
               move.b KIER(a1), d1 ; ...Get interrupt enable for save
               ori.b  #80, d1      ; ...add in set bit
               move.b d1, KBDIEN(a5) ; Place in LOCAL table
               move.b #57f, KIER(a1) ; Disable interrupts
               rts
;
;=====
; Init I/O Port Test Card to known state.
;
INITBOARD  clr.b d1      ; Init to zero
           move.b #57f, IER(a2) ; All interrupts off
           move.b d1, IFR(a2)
           move.b d1, ACR(a2) ; Aux control
           move.b d1, PCR(a2) ; Per control
           move.b d1, ORB(a2) ; Ports
           move.b d1, ORA(a2)
           move.b d1, DDRB(a2) ; Direction
           move.b d1, DDRA(a2)
           move.b d1, T1CL(a2) ; Timer #1
           move.b d1, T1CH(a2)
           move.b d1, T1LL(a2) ; Latch
           move.b d1, T1LH(a2)
           move.b d1, T2CL(a2) ; Timer #2
           move.b d1, T2CH(a2)
           move.b d1, SHR(a2) ; Shift register
           rts

           move.b #57f, IER(a3) ; All interrupts off
           move.b d1, IFR(a3)
           move.b d1, ACR(a3) ; Aux control
           move.b d1, PCR(a3) ; Per control
           move.b d1, ORB(a3) ; Ports
           move.b d1, ORA(a3)
           move.b d1, DDRB(a3) ; Direction
           move.b d1, DDRA(a3)
           move.b d1, T1CL(a3) ; Timer #1
           move.b d1, T1CH(a3)
           move.b d1, T1LL(a3) ; Latch
           move.b d1, T1LH(a3)
           move.b d1, T2CL(a3) ; Timer #2
           move.b d1, T2CH(a3)
           move.b d1, SHR(a3) ; Shift register
           rts
;
;=====
; Check data line connection to board.
;
CHECKLINE
  bsr   INITBOARD
  clr   d1      ; d1 holds data to write to 6522
@1     move.b d1, T1LL(a2) ; try writing to the 6522
       move.b T1LL(a2), d2 ; and reading back
       cmp.b  d1, d2      ; was the data the same?
       beq.s  @2
       cmpi.w #510, d5    ; Tech mode, ignore fails?
       beq.s  @2
       move.w #2, d7      ; Error, data line to test card is bad, or timer
       move.w #1, d0      ; Set fail flag
       bra.s  @3
;
@2     addq.b #1, d1      ; go thru all 256 data combinations to check
       bne.s  @1         ; data line connection to I/O board
       clr.w  d0         ; Set pass flag
@3     rts
;
;=====
; Check can get interrupt from I/O Port board.
;
CKINTERRUPT
  bsr   INITBOARD
  ori   #0700, sr      ; mask all interrupts
  move.b #5C0, IER(a2) ; enable timer 1 interrupts from parallel-port
  move.b #501, T1CL(a2) ; and set a short (1 usec) timeout interval
  move.b #500, T1CH(a2)
  NOP   ; wait a few microseconds for all the interrupt
  NOP   ; to be asserted
  NOP
  NOP
;
; set up new default interrupt routines for timer
  clr.w  d2      ; clear interrupt flag
  move.l (a4), a1 ; ...get vector address
  move.l a1, SAVEVECTOR(a5) ; ...Save old vector
  lea   INTTIMER, a1 ; New interrupt vector
  move.l a1, (a4) ; ...into vector

```

```

;
;   clr.w   d0           ;set pass flag, in case we make it thru
;   move    #$2200,sr    ; let the 6522 interrupt come thru
;   cmpl.w  #$03,d2     ; did we get the interrupt?
;   beq.s   @1          ;...yes, good
;   move.w  #3,d7       ;no, error
;   move.w  #1,d0       ;set error flag
;
;@1   MOVE    #$2700,SR   ;disable all interrupts and restore interrupt
;   move.l  SAVEVECTOR(a5),a1
;   move.l  a1,(a4)
;   move.b  #$40,IER(a2) ; turn off 6522 timer interrupts
;   RTS
;=====
; the following is interrupt
; handler for the preceding
; routine.
;=====
INTTIMER moveq  #303,d2   ; note the level 3 or up interrupt
;   move.b  #$40,IER(a2) ; disable the source
;   rts     ; and return
;
;=====
; Check registers on 6522(VIA)
CK1VIA  move.l  a2,a0     ;Get address of first VIA
;   bsr    DOCKVIA
;   rts
;
; Check registers on 6522(VIA)
CK2VIA  move.l  a3,a0     ;Get address of second VIA
;   bsr    DOCKVIA
;   rts
;
;
; DOCKVIA
;   bsr    INITBOARD
;   lea    AVAILABLE,a1  ;Registers that can be tested
;   clr    d3           ;Init counter
;
;@1   move.w  (a1),d2     ;See if legal register
;   beq    @4           ;...skip if zero
;
;   clr.l   d1           ; d1 holds data to write to 6522
;@2   move.l  a0,12(a6)   ; debug
;   move.b  d1,(a0)     ; try writing to the 6522
;   move.b  (a0),d2     ; and reading back
;   move.b  d1,18(a6)   ; debug
;   move.b  d2,20(a6)   ; debug
;   cmp.b  d1,d2       ; was the data the same?
;   beq.s  @3           ;
;   cmpl.w  #$12,d5     ; Tech mode to ignore fails?
;   beq.s  @3           ;
;   move.w  #2,d7       ; Error, register wrong
;   move.w  #1,d0       ; Set fail flag
;   bra.s  @10
;
;@3   addq.b  #1,d1     ; go thru all 256 data combinations to check
;   bne.s  @2           ; data line connection to I/O board
;   clr.b  (a0)        ; Set to 0 on exit
;
;@4   addq.b  #1,d3     ; Increment counter
;   adda  #8,a0        ; Next register
;   adda  #2,a1
;   cmp.w  #13,d3
;   bmi   @1
;
;   clr.w  d0          ; Set pass flag
;@10  rts
;
;=====
; Check timers on 6522(VIA)
CK1TIMER move.l  a2,a0     ;Get address of first VIA
;   bsr    CKTIMER
;   rts
;
; Check timers on 6522(VIA)
CK2TIMER move.l  a3,a0     ;Get address of second VIA
;   bsr    CKTIMER
;   rts
;
;
; CKTIMER
;   bsr    INITBOARD
;   clr.w  d0
;   move.w  d0,WhichTimer(a5) ; Init to timer #1
;   move.b  #0,ACR(a0)     ; Set for one-shot interrupt
;   move.b  #$C0,IER(a0)  ; Enable Timer
;
; init interrupt address
;   ori.w  #$0700,sr     ; Disable interrupts
;   lea   INTCARD,a1
;   move.l (a1),a4
;   move.l (a4),a1       ;...get vector address
;   move.l a1,SAVEVECTOR(a5) ;...Save old vector

```

```

    lea    ITIMER,a1      ;New interrupt vector
    move.l a1,(a4)       ;... into vector
    move   #$2100,sr     ; let the 6522 interrupt come thru
;
@99    lea    EXPECT,a4   ;Expect times
    lea    TESTVALUES,a1
    clr.w  d3           ;Test value counter
@1     clr.w  T1(a5)     ;clear happened flag
;
    clr.w  d2           ;Init counter for loops done
    move.w 44(a1),d0     ;Get MSB
    move.w (a1)+,d4     ;Get LSB
    move.w WhichTimer(a5),d1
    bne    @100
    move.b d4,T1CL(a0)  ;Load counter low
    move.b d0,T1CH(a0) ;Load upper and start counter
    bra   @2
;
@100   move.b d4,T2CL(a0) ;Load counter low
    move.b d0,T2CH(a0) ;Load upper and start counter
    bra   @2           ;this keeps paths equal
;
;!!!! Critical loop, any changes require expect table changes
; this loop measured at about 13us
@2     cmpi.w #0,T1(a5)  ;check for happened flag           ( 8)
    bne    @3           ;...exit on flag                 ( 8)
    add.w  #1,d2        ;increment timeout timer         ( 4)
    cmp.w  #$7ff0,d2   ;...exit on overtime           ( 4)
    bpl   @3           ;                               ( 8)
    move.b (a0),d0     ;Dummy for timing software loop ( 8)
    bra   @2           ;Continue wait                    (12)
;!!!! End of critical loop
;
@3     move.w d2,(a6)   ;DEBUG save
    move.w  T1(a5),d1
    cmpi.w #33,d5     ;Tech modes to ignore fails?
    beq   @4
    cmp.w  (a4),d2    ;Compare to low limit
    bmi   @7
    move.w 44(a4),d0  ;Compare to high limit
    cmp.w  d0,d2
    bpl   @8
@4     adda  #2,a6
    adda  #2,a4
;
    add.w  #1,d3      ;Increment test value counter
    cmpi.w #22,d3
    bmi   @1
    adda  #2,a6
    move.w WhichTimer(a5),d0
    beq   @10
;
@5     clr.w  d0
    move.b #$7f,IER(a0) ;Disable Timer #1
    MOVE   #$2700,SR   ;disable all interrupts and restore interrupt
    lea   INTCARD,a1
    move.l (a1),a4
    move.l SAVEVECTOR(a5),a1
    move.l a1,(a4)
    rts
;
@6     move.w #1,d0    ;Set error flag
    bra   @5
;
; Timer was too fast, time is too short
@7     move.w #4,d7
    move.w  #1,d0
    bra   @5
;
; Timer was too slow, time is too long
@8     move.w #5,d7
    move.w  #1,d0
    bra   @5
;
; =====
@10    add.w  #1,d6    ;Next Step number
    move.w  #1,d0
    move.w  d0,WhichTimer(a5)
    move.b  #$7f,IER(a0) ;Disable Timer #1
    move.b  #$A0,IER(a0) ;Enable Timer #2
    bra   @99
;
; =====
; Interrupt routine for timer test.
ITIMER movem.l a0-a2/d0,-(sp) ;save registers on interrupt entry
    move.b IFR(a0),d0      ;See if timer #1
    btst  #6,d0           ;...timer 1 flag
    beq   @1             ;...not timer if flag zero
    move.b T1CL(a0),d0    ;reset timer1 interrupt
    move.w #$11,T1(a5)   ;set happened flag
    bra   @2
;
@1     btst  #5,d0      ;Is it timer #2 interrupt?
    beq   @2           ;...no, ignore any others

```

```

move.b T2CL(a0),d0 ;Clear interrupt
move.w #S22,T1(a5) ;...yes, set flag to program
;
@2 movem.l (sp)+,a0-a2/d0 ;restore regs on interrupt exit
rte
;
;-----
PA0to7 ;Check connection thru cable
bsr INITBOARD
;
move.b #S0C, DDRB(a2) ;PB 2,3 outputs
move.b #S00, ORB(a2)
move.b #S0C, DDRB(a3) ;PB 2,3 outputs
move.b #S08, ORB(a3)
move.b #SFF, DDRA(a2) ;All outputs
;
cmp.w #10,d5 ;Cycle tech mode?
beq @20
cmp.w #11,d5 ;Cycle tech mode?
beq @1
;
move.w #Sff,d3
move.b d3,ORA(a2)
nop
move.b ORA(a3),d0
cmp.b d3,d0
bne @11
;
move.w #S00,d3
move.b d3,ORA(a2)
nop
move.b ORA(a3),d0
cmp.b d3,d0
bne @11
;
move.w #S55,d3
move.b d3,ORA(a2)
nop
move.b ORA(a3),d0
cmp.b d3,d0
bne @11
;
move.w #SAA,d3
move.b d3,ORA(a2)
nop
move.b ORA(a3),d0
cmp.b d3,d0
bne @11
;
@1 clr.w d0
move.b d0,DDRA(a2)
move.b d0, DDRB(a2)
move.b d0,DDRA(a3)
move.b d0, DDRB(a3)
;
move.b #S0C, DDRB(a3) ;PB 2,3 outputs
move.b #S00, ORB(a3)
move.b #S0C, DDRB(a2) ;PB 2,3 outputs
move.b #S08, ORB(a2)
move.b #SFF, DDRA(a3) ;All outputs
cmp.w #11,d5
beq @21
;
move.w #Sff,d3
move.b d3,ORA(a3)
nop
move.b ORA(a2),d0
cmp.b d3,d0
bne @12
;
move.w #S00,d3
move.b d3,ORA(a3)
nop
move.b ORA(a2),d0
cmp.b d3,d0
bne @12
;
move.w #S55,d3
move.b d3,ORA(a3)
nop
move.b ORA(a2),d0
cmp.b d3,d0
bne @12
;
move.w #SAA,d3
move.b d3,ORA(a3)
nop
move.b ORA(a2),d0
cmp.b d3,d0
bne @12
;
@10 rts
;
@11 move.w d0,d4 ;Actuel, d3 contains expected
move.w #6,d7

```



```

        bra      @10
;
@12      move.w  d0,d4      ;Actual, d3 contains expected
        move.w  #7,d7
        bra      @10
;
; Tech mode loop, send data from port A to port B
@20      move.b  #$55,ORA(a2)
        move.b  #$AA,ORA(a2)
        bra      @20
;
; Tech mode loop, send data from port B to port A
@21      move.b  #$55,ORA(a3)
        move.b  #$AA,ORA(a3)
        bra      @21
;
;=====
PB0and7  ;Check connection thru cable PB0,PB7
        bsr      INITBOARD
;
        move.b  #$8C, DDRB(a2) ;PB 2,3,7 output
        move.b  #$0C, DDRB(a3) ;PB 0 input
        move.b  #$00, ORB(a3)
        cmp.w   #12,d5
        beq     @20
        cmp.w   #13,d5
        beq     @1
;
        move.w  #$80,d3
        move.b  d3,ORB(a2)
        move.w  #$01,d3
        nop
        nop
        move.b  ORB(a3),d0
        and.w   #$0001,d0
        cmp.b  d3,d0
        bne    @11
;
        move.w  #$00,d3
        move.b  d3,ORB(a2)
        nop
        move.b  ORB(a3),d0
        and.w   #$0001,d0
        cmp.b  d3,d0
        bne    @11
;
@1        move.b  #$8C, DDRB(a3) ;PB 2,3,7 output
        move.b  #$0C, DDRB(a2) ;PB 0 input
        move.b  #$00, ORB(a2)
        cmp.w   #13,d5
        beq     @21
;
        move.w  #$80,d3
        move.b  d3,ORB(a3)
        move.w  #$01,d3
        nop
        move.b  ORB(a2),d0
        and.w   #$0001,d0
        cmp.b  d3,d0
        bne    @12
;
        move.w  #$00,d3
        move.b  d3,ORB(a3)
        nop
        move.b  ORB(a2),d0
        and.w   #$0001,d0
        cmp.b  d3,d0
        bne    @12
;
@10      rts
;
;
@11      move.w  d0,d4      ;Actual, d3 contains expected
        move.w  #8,d7
        bra      @10
;
;
@12      move.w  d0,d4      ;Actual, d3 contains expected
        move.w  #9,d7
        bra      @10
;
; Tech mode loop
@20      move.b  #$80,ORB(a2)
        move.w  #$00,ORB(a2)
        bra      @20
;
; Tech mode loop
@21      move.b  #$80,ORB(a3)
        move.w  #$00,ORB(a3)
        bra      @21
;
;=====
PB4and6  ;Check connection thru cable PB4,PB6
        bsr      INITBOARD
;
        move.b  #$1C, DDRB(a2) ;PB 2,3,4 output

```

```

move.b  #0C, DDRB(a3) ;PB 6 input
move.b  #00, ORB(a3)
cmp.w   #14, d5      ;Tech mode?
beq     @20
cmp.w   #15, d5
beq     @1

;
move.w   #10, d3
move.b  d3, ORB(a2)
move.w   #40, d3
nop
nop
move.b  ORB(a3), d0
and.w   #0040, d0
cmp.b   d3, d0
bne    @11

;
move.w   #00, d3
move.b  d3, ORB(a2)
nop
move.b  ORB(a3), d0
and.w   #0040, d0
cmp.b   d3, d0
bne    @11

;
@11      move.b  #1C, DDRB(a3) ;PB 2,3,4 output
         move.b  #0C, DDRB(a2) ;PB 6 input
         move.b  #00, ORB(a2)
         cmp.w   #15, d5
         beq     @21

;
         move.w   #10, d3
         move.b  d3, ORB(a3)
         move.w   #40, d3
         nop
         move.b  ORB(a2), d0
         and.w   #0040, d0
         cmp.b   d3, d0
         bne    @12

;
         move.w   #00, d3
         move.b  d3, ORB(a3)
         nop
         move.b  ORB(a2), d0
         and.w   #0040, d0
         cmp.b   d3, d0
         bne    @12

;
@10      rts

;
@11      move.w   d0, d4      ;Actual, d3 contains expected
         move.w   #10, d7
         bra     @10

;
@12      move.w   d0, d4      ;Actual, d3 contains expected
         move.w   #11, d7
         bra     @10

;
; Tech mode
@20      move.b  #10, ORB(a2)
         move.w   #00, ORB(a2)
         bra     @20

;
; Tech mode
@21      move.b  #10, ORB(a3)
         move.w   #00, ORB(a3)
         bra     @21

;
;=====
PB3andCB1 ;Check connection thru cable PB3, CB1
         bsr     INITBOARD

;
; Setup vector to expect CB1 interrupt
         ori.w   #0700, sr      ;Disable interrupts
         lea   INTCARD, a1
         move.l (a1), a4
         move.l (a4), a1      ;...get vector address
         move.l a1, SAVEVECTOR(a5) ;...Save old vector
         lea   ICBI1, a1      ;New interrupt vector
         move.l a1, (a4)      ;...into vector
         move   #2100, sr      ; let the 6522 interrupt come thru

;
         move.b  #0C, DDRB(a2) ;PB 2,3 output
         move.b  #00, ORB(a2) ;make an output gate
         move.b  #0C, DDRB(a3) ;CB1 input
         move.b  #08, ORB(a3) ;Make an input gate

;
; Set PCR to interrupt on high going edge
         move.b  #10, PCR(a3)
         move.w   #00, CB1VIA1(a5) ;clear happened flag

;
; Enable CB1 interrupt capability
         move.b  #7f, IFR(a3) ;All flags off
         move.b  #90, IER(a3)

```

```

    cmp.w #16,d5 ;Tech mode loop?
    beq @20
    cmp.w #17,d5 ;Tech mode loop?
    beq @1
;
; Wait and assure no interrupts
    nop
    nop
    move.w CB1VIA1(a5),d0
    cmp.w #0,d0
    bne @12
;
; Drive a 1 out of PB3
    move.b #$08,ORB(a2)
    nop
    nop
;
; Check to see if got interrupt, fail if did not.
    move.w CB1VIA1(a5),d0
    cmp.w #0,d0
    beq @13
;
; Reset got interrupt flag
    move.w #0,CB1VIA1(a5)
;
; Drive a 0 out of PB3
    move.b #$00,ORB(a2)
    nop
    nop
;
; Check an assure no interrupt
    move.w CB1VIA1(a5),d0
    cmp.w #0,d0
    bne @12
;
; Drive a 1 out of PB3
    move.b #$08,ORB(a2)
    nop
    nop
;
; Check to see if got interrupt, fail if did not.
    move.w CB1VIA1(a5),d0
    cmp.w #0,d0
    beq @13
;
; Disable CB1 interrupt.
@1 move.b #$7F,IER(a2)
;
; Setup vector to expect CB1 interrupt
    ori.w #$0700,sr ;Disable interrupts
    lea INTCARD,a1
    move.l (a1),a4
    lea ICB1V2,a1 ;New interrupt vector
    move.l a1,(a4) ;... into vector
    move #$2100,sr ; let the 6522 interrupt come thru
;
    move.b #$0C,DDRB(a3) ;PB 2,3 output
    move.b #$00,ORB(a3) ;make an output gate
    move.b #$0C,DDRB(a2) ;CB1 input
    smove.b #$08,ORB(a2) ;Make an input gate
;
; Set PCR to interrupt on high going edge
    move.b #$10,PCR(a2)
    move.w #$00,CB1VIA2(a5) ;clear happened flag
;
; Enable CB1 interrupt capability
    move.b #$7f,IFR(a2) ;All flags off
    move.b #$90,IER(a2)
;
    cmp.w #17,d5 ;Tech mode loop
    beq @21
;
; Wait and assure no interrupts
    nop
    nop
    move.w CB1VIA2(a5),d0
    cmp.w #0,d0
    bne @11
;
; Drive a 1 out of PB3
    move.b #$08,ORB(a3)
    nop
    nop
;
; Check to see if got interrupt, fail if did not.
    move.w CB1VIA2(a5),d0
    cmp.w #0,d0
    beq @14
;
; Reset got interrupt flag
    move.w #0,CB1VIA2(a5)
;
; Drive a 0 out of PB3
    move.b #$00,ORB(a3)
    nop

```

```

nop
; Check an assure no interrupt
move.w CB1VIA2(a5),d0
cmp.w #0,d0
bne @11
; Drive a 1 out of PB3
move.b #$08,ORB(a3)
nop
nop
; Check to see if got interrupt, fail if did not.
move.w CB1VIA2(a5),d0
cmp.w #0,d0
beq @14
; Disable CB1 interrupt.
move.b #$7F,IER(a3)
;
;
; Restore vector to original
MOVE #$2700,SR ;disable all interrupts and rest interrupt
lea INTCARD,a1
move.l (a1),a4
move.l SAVEVECTOR(a5),a1
move.l a1,(a4)
;
@10 rts
;
; Extraneous interrupt error on part A
@11 move.w #12,d7
bra @10
;
; Extraneous interrupt error on part B
@12 move.w #13,d7
bra @10
;
; Expected interrupt did not occur on part B
@13 move.w #14,d7
bra @10
;
; Expected interrupt did not occur on part A
@14 move.w #15,d7
bra @10
;
; Tech mode loop
@20 move.b #$08,ORB(a2) ; Drive a 1 out of PB3
nop
nop
move.b #$00,ORB(a2) ; Drive a 0 out of PB3
nop
nop
bra @20
;
; Tech mode loop
@21 move.b #$08,ORB(a3) ; Drive a 1 out of PB3
nop
nop
move.b #$00,ORB(a3) ; Drive a 0 out of PB3
nop
nop
bra @21
;
; Interrupt routine for PB3 to CB1 test.
ICB1V1 move.l d0,-(sp) ;save registers on interrupt entry
move.b IFR(a3),d0 ;See if CB1
btst #4,d0 ;...CB1 flag
beq @1 ;...not CB1 if flag zero
tst.b ORB(a3) ;reset CB1 interrupt
move.w #$01,CB1VIA1(a5) ;set happened flag
;
@1 move.l (sp)+,d0 ;restore regs on interrupt exit
rts
;
; Interrupt routine for PB3 to CB1 test.
ICB1V2 move.l d0,-(sp) ;save registers on interrupt entry
move.b IFR(a2),d0 ;See if CB1
btst #4,d0 ;...CB1 flag
beq @1 ;...not CB1 if flag zero
tst.b ORB(a2) ;reset CB1 interrupt
move.w #$01,CB1VIA2(a5) ;set happened flag
;
@1 move.l (sp)+,d0 ;restore regs on interrupt exit
rts
;
;=====  

CA2andPB1 ;Check connection thru cable CA2,PB1
bsr INITBOARD

```

```

; Setup vector to expect CA1 interrupt
ori.w  #0700,sr      ;Disable interrupts
lea    INTCARD,a1
move.l (a1),a4
move.l (a4),a1      ;...get vector address
move.l a1,SAVEVECTOR(a5);...Save old vector
lea    ICA1V1,a1    ;New interrupt vector
move.l a1,(a4)     ;... into vector
move   #$2100,sr   ; let the 6522 interrupt come thru

;
move.b #$0C,DDR(a2); PB 2,3 output
move.b #$00,ORB(a2); make an output gate
move.b #$0C,DDR(a3); PB1 input
move.b #$08,ORB(a3); Make an input gate

;
move.b #$0C,PCR(a2); Drive CA2 Low
; Set PCR to interrupt on high going edge
move.b #$01,PCR(a3)
move.w #$00,CA1VIA1(a5); clear happened flag

; Enable CB1 interrupt capability
move.b #$7f,IFR(a3); All flags off
move.b #$82,IER(a3)

;
cmp.w  #18,d5      ;Tech mode loop?
beq    @20
cmp.w  #19,d5
beq    @1

; Wait and assure no interrupts
nop
nop
move.w CA1VIA1(a5),d0
cmp.w  #0,d0
bne   @11

;
move.b #$0E,PCR(a2); Drive CA2 High
nop
nop

; Check to see if got interrupt, fail if did not.
move.w CA1VIA1(a5),d0
cmp.w  #0,d0
beq    @12

; Check PB1 for constant level
move.b ORB(a3),d0
and.b  #$02,d0
cmp.b  #$02,d0
bne   @17

; Reset got interrupt flag
move.w #0,CA1VIA1(a5)

;
move.b #$0C,PCR(a2); Drive CA2 Low
nop
nop

; Check an assure no interrupt
move.w CA1VIA1(a5),d0
cmp.w  #0,d0
bne   @11

; Check PB1 for constant level
move.b ORB(a3),d0
and.b  #$02,d0
cmp.b  #$00,d0
bne   @17

;
move.b #$0E,PCR(a2); Drive CA2 High
nop
nop

; Check to see if got interrupt, fail if did not.
move.w CA1VIA1(a5),d0
cmp.w  #0,d0
beq    @12

; Check PB1 for constant level
move.b ORB(a3),d0
and.b  #$02,d0
cmp.b  #$02,d0
bne   @17

;
; Disable CB1 interrupt.
@1:   move.b #$7F,IER(a2)

;
; Setup vector to expect CA1 interrupt
ori.w  #0700,sr      ;Disable interrupts
lea    INTCARD,a1
move.l (a1),a4
lea    ICA1V2,a1    ;New interrupt vector
move.l a1,(a4)     ;... into vector
move   #$2100,sr   ; let the 6522 interrupt come thru

```

```

    move.b #S0C, DDRB(a3) ;PB 2,3 output
    move.b #S00, ORB(a3) ;make an output gate
    move.b #S0C, DDRB(a2) ;PB1 input
    move.b #S08, ORB(a2) ;Make an input gate

;
;
; Set PCR to interrupt on high going edge
    move.b #S0C, PCR(a3) ;Drive CA2 Low
    move.b #S01, PCR(a2)
    move.w #S00, CA1VIA2(a5) ;clear happened flag

; Enable CB1 interrupt capability
    move.b #S7F, IFR(a2) ;All flags off
    move.b #S82, IER(a2)

;
    cmp.w #19, d5 ;Tech mode loop?
    beq @21

; Wait and assure no interrupts
    nop
    nop
    move.w CA1VIA2(a5), d0
    cmp.w #0, d0
    bne @14

;
    move.b #S0E, PCR(a3) ;Drive CA2 High
    nop
    nop

; Check to see if got interrupt, fail if did not.
    move.w CA1VIA2(a5), d0
    cmp.w #0, d0
    beq @13

; Check PB1 for constant level
    move.b ORB(a2), d0
    and.b #S02, d0
    cmp.b #S02, d0
    bne @18

; Reset got interrupt flag
    move.w #0, CA1VIA2(a5)

;
    move.b #S0C, PCR(a3) ;Drive CA2 Low
    nop
    nop

; Check and assure no interrupt
    move.w CA1VIA2(a5), d0
    cmp.w #0, d0
    bne @14

; Check PB1 for constant level
    move.b ORB(a2), d0
    and.b #S02, d0
    cmp.b #S00, d0
    bne @18

;
    move.b #S0E, PCR(a3) ;Drive CA2 High
    nop
    nop

; Check to see if got interrupt, fail if did not.
    move.w CA1VIA2(a5), d0
    cmp.w #0, d0
    beq @13

; Check PB1 for constant level
    move.b ORB(a2), d0
    and.b #S02, d0
    cmp.b #S02, d0
    bne @18

; Disable CB1 interrupt.
    move.b #S7F, IER(a3)

;
;
; Restore vector to original
    MOVE #S2700, SR ;disable all interrupts and reset interrupt
    lea INTCARD, a1
    move.l (a1), a4
    move.l SAVEVECTOR(a5), a1
    move.l a1, (a4)

;
@10 rts

; Interrupt occurred when none expected, on Port B.
@11 move.w #13, d7
    bra @10

; Expected interrupt did not occur on port B.
@12 move.w #14, d7

```



```

move.b IFR(a2),d4 ;Read see if CB2 was flagged.
move.w d4,44(a1) ;...save actual
move.w (a1)+,d1
eor.w d1,d4 ;Only leave CB2 difference
and.w #$08,d4
cmp.w #0,d4
bne @12

move.w ParityTests(a5),d0
add.w #1,d0
move.w d0,ParityTests(a5)
cmp.w #22,d0
bne @1

; End of loop
@10 rts

; Bad data (PA0-PA7) during parity test.
@11 move.w #20,d7
bra @10

; Bad parity (CB2) during parity test.
@12 move.w #21,d7
bra @10

;Tech Mode loop
@20 move.b #$01,ORA(a3) ;Data
move.b #$01,ORB(a3) ;Parity line
move.b #$08,ORB(a2) ;Pulse reset line high
move.b #$28,ORB(a2) ; reset line low
move.b #$08,IFR(a2) ;Reset CB2 flag in case it was set
move.b ORA(a2),d3 ;Read port A
move.b IFR(a2),d4 ;Read see if CB2 was flagged.

move.b #$03,ORA(a3) ;Data
move.b #$01,ORB(a3) ;Parity line
move.b #$08,ORB(a2) ;Pulse reset line high
move.b #$28,ORB(a2) ; reset line low
move.b #$08,IFR(a2) ;Reset CB2 flag in case it was set
move.b ORA(a2),d3 ;Read port A
move.b IFR(a2),d4 ;Read see if CB2 was flagged.
bra @20

;-----
;
BParity
; DDRA set to inputs, A port
bsr INITBOARD

move.b #$FF,DDRA(a2) ;Make port B output data
move.b #$1C,DDRB(a2) ;PB 2,3,4 output
move.b #$00,ORB(a2) ;Make an output gate

move.b #$2C,DDRB(a3) ;PB 2,3,5 output
move.b #$08,ORB(a3) ;make an input gate
move.b #$6A,PCR(a3) ;CA2 pulse output, CB2 pos edge ind inter

cmp.w #21,d5
beq @20

lea PData,a0
lea PExpect,a1.
clr.w ParityTests(a5) ;Clear test number counter
@1
move.w (a0),d0
move.b d0,ORA(a2) ;Data
move.w 44(a0),d1
adda #2,a0
move.b d1,ORB(a2) ;Parity line
move.b #$08,ORB(a3) ;Pulse reset line high
move.b #$28,ORB(a3) ; reset line low
move.b #$08,IFR(a3) ;Reset CB2 flag in case it was set
move.b ORA(a3),d3 ;Read port A
cmp.b d0,d3 ;...assure data is correct
bne @11
clr.w d4
move.b IFR(a3),d4 ;Read see if CB2 was flagged.
move.w d4,44(a1) ;...save actual
move.w (a1)+,d1
eor.w d1,d4 ;Only leave CB2 difference
and.w #$08,d4
cmp.w #0,d4
bne @12

move.w ParityTests(a5),d0
add.w #1,d0
move.w d0,ParityTests(a5)
cmp.w #22,d0
bne @1

; End of loop
@10 rts

; Bad data (PA0-PA7) during parity test.
@11 move.w #22,d7
bra @10

```



```

; Bad parity (CB2) during parity test.
@12      move.w  #23,d7
        bra     @10

```

```

; Tech Mode loop
@20      move.b  #01,ORA(a2) ;Data
        move.b  #01,ORB(a2) ;Parity line
        move.b  #08,ORB(a3) ;Pulse reset line high
        move.b  #28,ORB(a3) ; reset line low
        move.b  #08,IFR(a3) ;Reset CB2 flag in case it was set
        move.b  ORA(a3),d3   ;Read port A
        move.b  IFR(a3),d4   ;Read see if CB2 was flagged.

        move.b  #03,ORA(a2) ;Data
        move.b  #01,ORB(a2) ;Parity line
        move.b  #08,ORB(a3) ;Pulse reset line high
        move.b  #28,ORB(a3) ; reset line low
        move.b  #08,IFR(a3) ;Reset CB2 flag in case it was set
        move.b  ORA(a3),d3   ;Read port A
        move.b  IFR(a3),d4   ;Read see if CB2 was flagged.
        bra     @20

```

Restore VIA for next user

```

RESTORE
        move    #$2700,sr    ;Disable interrupts
;
        lea    KBDVIA,a1    ;Enable keyboard COPS
        move.b #$7f,IER(a1)
        move.b KBDIEN(a5),d0 ;Get from LOCAL table
        move.b d0,IER(a1)

        clr.b  ACR(a2)
        move.b #$7f,IFR(a2)
        move.b #$7f,IER(a2) ;All interrupts off
        clr.b  ACR(a3)
        move.b #$7f,IFR(a3)
        move.b #$7f,IER(a3) ;All interrupts off
        rts

```

```

CARD      .WORD 0,0 ;Card base address, where boot ROM is
INTCARD   .WORD 0,0 ;Int vector for card
;
LOCAL     .WORD 0 ;TICKTOCK
          .WORD 0 ;T1
          .WORD 0 ;T2
          .WORD 0 ;KBDIEN
          .WORD 0,0 ;SAVEVECTOR
          .WORD 0 ;WhichTimer
          .WORD 0 ;CA1VIA1
          .WORD 0 ;CA1VIA2
          .WORD 0 ;CB1VIA1
          .WORD 0 ;CB1VIA2
          .WORD 0 ;ParityTests

```

Tables derived from National LOGIC databook for LS280, P6-204

```

PData     .WORD $00 ;Data for PA0-PA7
          .WORD $01,$02,$04,$07
          .WORD $03,$06,$05
          .WORD $08,$10,$20,$38
          .WORD $18,$30,$28
          .WORD $40,$80,$00,$C0
          .WORD $C0,$80,$40
          .WORD $00 ;Parity sent, PB6
          .WORD $00,$00,$00,$00
          .WORD $00,$00,$00
          .WORD $00,$00,$00,$00
          .WORD $00,$00,$00
          .WORD $00,$00,$10,$10
          .WORD $00,$10,$10
; Expect $08 = expect CB2 interrupt, 0 = no interrupt expected
PExpect   .WORD $08 ;Expected
          .WORD $00,$00,$00,$00
          .WORD $08,$08,$08
          .WORD $00,$00,$00,$00
          .WORD $08,$08,$08
          .WORD $00,$00,$00,$00
          .WORD $08,$08,$08
          .WORD $00 ;Actual;
          .WORD $00,$00,$00,$00
          .WORD $00,$00,$00
          .WORD $00,$00,$00,$00
          .WORD $00,$00,$00
          .WORD $00,$00,$00,$00
          .WORD $00,$00,$00

```

Flag for table end and debug

```

        .WORD $1234,$5678

```



%  
a+C  
TWOP.HDR  
TOPORT.LT  
■  
%%

